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TEST REPORT

TAS Test for A3LSMM356B

APPLICANT
Samsung Electronics. Co., Ltd.

REPORT NO.
HCT-SR-2403-FC002

DATE OF ISSUE
Mar. 21, 2024

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TEST REPORT

FCC TAS Test for certification

REPORT NO.
HCT-SR-2403-FC002

DATE OF ISSUE
Mar. 21, 2024

FCC ID
A3LSMM356B

Applicant	SAMSUNG Electronics Co., Ltd 129, Samsung-ro, Yeongtong-gu, Suwon-Si, Gyeonggi-do, 16677, Korea
Product Name	**Mobile Phone**
Model Name	**SM-M356B/DS**
Date of Test	**Mar. 19, 2024 ~ Mar. 21, 2024**
Location of Test	■ Permanent Testing Lab □ On Site Testing Lab (Address: 74, Seoicheon-ro 578beon-gil, Majang-myeon, Icheon-si,
FCC Rule Part(s)	CFR §2.1093
Test Results	**PASS**

REVISION HISTORY

The revision history for this test report is shown in table.

Revision No.	Date of Issue	Description
0	Mar. 21, 2024	Initial Release

Notice

Content
The results shown in this test report only apply to the sample(s), as received, provided by the applicant, unless otherwise stated. The test results have only been applied with the test methods required by the standard(s). The laboratory is not accredited for the test results marked *. Information provided by the applicant is marked **. Test results provided by external providers are marked ***. When confirmation of authenticity of this test report is required, please contact www.hct.co.kr The test results in this test report are not associated with the ((KS Q) ISO/IEC 17025) accreditation by KOLAS (Korea Laboratory Accreditation Scheme) / A2LA (American Association for Laboratory Accreditation) that are under the ILAC (International Laboratory Accreditation Cooperation) Mutual Recognition Agreement (MRA).

CONTENTS

1. Introduction

This Process of TAS Validation is to demonstrate that the DUT complies with FCC RF exposure compliance requirement under varying Tx power transmission scenarios, thus validation the Samsung S.LSI TAS algorithm feature for FCC equipment authorization of the mobile phone. The value of Plimit used in this report per scenarios are determined.

FCC RF exposure limits are comprised of SAR (Specific Absorption Rate) and limits depending on frequency of operation. Both SAR regulatory specifications are defined over certain measurement duration allowing for time-averaging. The Samsung S.LSI proprietary TAS (Time Average SAR) algorithm has been designed to meet the compliance limits over the required duration, while still allowing dynamic control of transmit power for meeting system performance.

1.1 RF Exposure Limits for Frequencies < 6 GHz

HUMAN EXPOSURE	UNCONTROLLED ENVIRONMENT General Population (W/kg) or (mW/g)	CONTROLLED ENVIRONMENT Occupational (W/kg) or (mW/g)
SPATIAL PEAK SAR * (Partial Body)	1.6	8.0
SPATIAL AVERAGE SAR ** (Whole Body)	0.08	0.4
SPATIAL PEAK SAR *** (Hands / Feet / Ankle / Wrist)	4.0	20.0

NOTES:

* The Spatial Peak value of the SAR averaged over any 1 g of tissue (defined as a tissue volume in the shape of a cube) and over the appropriate averaging time.

** The Spatial Average value of the SAR averaged over the whole-body.

*** The Spatial Peak value of the SAR averaged over any 10 g of tissue (defined as a tissue volume in the shape of a cube) and over the appropriate averaging time.

1.2 Interim Guidance for Time Averaging

Per October 2018 TCB Workshop Notes, the below time- averaging windows can be used for assessing time- averaged exposures for devices that are capable of actively monitoring and adjusting power output over time to comply with exposure limits.

Interim Guidance	Frequency (GHz)	Maximum Averaging Time (sec)
SAR	< 3	100
	3 – 6	60
MPE	6 - 10	30
	10 - 16	14
	16 – 24	8
	24 – 42	4
	42 – 95	2

2. Test Result of the DUT

2.1 Measurement Results Summary Table

Test Case #	Test Scenario	Tech	Band	Antenna	RSI	SAR Limit 1g [W/kg]	Max averaged time1g SAR[W/kg]	Test Results
1-1	Time-varying Tx power transmission	LTE	66	Main 2	2	1.6	0.339	Verified
1-2							0.317	Verified
2-1		LTE	41	Main 2	2	1.6	0.195	Verified
2-2							0.181	Verified
3-1		SA/FR1	66	Main 2	2	1.6	0.286	Verified
3-2							0.277	Verified
4-1		SA/FR1	41	Main 2	2	1.6	0.246	Verified
4-2							0.235	Verified
5-1		SA/FR1	77	Sub 2	2	1.6	0.387	Verified
5-2							0.322	Verified
6-1	Change in Call	LTE	66	Main 2	2	1.6	0.323	Verified
6-2		LTE	41	Main 2	2	1.6	0.190	Verified
7-1	Re-selection	SA/FR1	66	Main 2	2	1.6	0.280	Verified
		LTE	41	Main 2	2			
7-2		SA/FR1	41	Main 2	2	1.6	0.363	Verified
		LTE	66	Main 2	2			
8-1	SAR exposure switch	NSA/FR1	66	Main 2	2	1.6	0.604	Verified
		LTE	26	Main 1	2			
8-2		NSA/FR1	41	Main 2	2	1.6	0.607	Verified
		LTE	26	Main 1	2			
9	RSI Change	SA/FR1	66	Main 2	2-1	1.6	0.280	Verified
10-1	TAS to Non TAS	LTE	66	Main 2	2	1.6	0.607	Verified
		UMTS	5	Main 1	2	1.6		
10-2		LTE	41	Main 2	2	1.6	0.683	
		UMTS	5	Main 1	2	1.6		
11-1	WCDMA time varying Tx power	UMTS	2	Main 2	2	1.6	0.165	Verified
11-2							0.163	
12-1	2G time varying Tx power	2G	GSM 1900	Main 2	2	1.6	0.525	Verified
12-2							0.533	
13	Antenna Switching with Spatial TAS	SA/FR1	41	Main 2	2	1.6	0.491	Verified
			77	Sub 2	2			
14	NSA with Spatial TAS	LTE	66	Main 2	2	1.6	0.453	Verified
		NSA/FR1	77	Sub 2	2			
15	NSA antenna switching with Spatial TAS	LTE	26	Main 1	2	1.6	0.500	Verified
		NSA/FR1	41	Main 2	2			
		NSA/FR1	77	Sub 2	2			

Note: RSI (1) – Reduced-RCV ON, RSI (2) – Reduced-Hotspot Mode ON

FCC SAR Limit [W/kg]: 1.6W/kg,1g / Total exposure Limit :1.0

3. Tx Varying Transmission Test Cases and Test Proposal.

The following scenarios are covered in this report to demonstrate compliance with FCC RF exposure in Tx-varying transmission conditions.

1. During a time-varying Tx power transmission – to prove that TAS feature accounts for Tx power variations in time accurately.
2. During a call disconnect and re-establish scenario – to prove that the TAS feature accounts for history of Tx power from past accurately
3. During a technology/band handover – to prove that TAS feature accounts for history across transitions in band/technology
4. During RSI (Radio SAR index) change – to prove that TAS feature functions correctly to meet compliance limits across RSI changes
5. During UL CA- to prove that TAS feature can handle adding/removing CC and can handle both single CC and CA

As described in SAR Char. Report, the RF exposure is proportional to the Tx power for FR1. Thus, we rely on conducted power measurements (FR1) dynamic case to demonstrate that overall RF exposure is within the FCC limit.

The overall procedure for validating the test is summarized below:

1. Measure conducted power (FR1) over time, denoted as $TxPower(t)$, with time index t
2. Convert measured powers to RF exposure values using linear relationship shown below. In below expression, $P_{limit,FR1}$ would be the measured power at which FR1 technology meets

$$SAR(t) = \frac{TxPower(t)}{P_{limit,FR1}} \times SAR\_design\_target$$

measured SAR level of SAR_design_target as described in SAR Char Report. Eqn. (1)

3. Compute the average RF exposure over the most recent measurement duration which are denoted as TSAR for FR1, respectively. These durations are as specified by FCC. This measurement duration interval is then given by $[t - T_{SAR}, t]$ for FR1, respectively

4. Divide the RF exposure for FR1 by corresponding FCC limits and ensure the sum denoted as TER (total exposure ratio) is less than 1 for all t. Please refer following to following equations which describe the calculation of TER and its target constraint. The expressions below is general considering a number of FR1 radios in general denoted by L_{SAR}.

For FR1 transmissions only:

$$\sum_{l_{SAR}=0}^{L_{SAR}-1} \frac{\frac{1}{T_{SAR}} \int_{t-T_{SAR}}^{t} SAR_{l_{SAR}}}{FCC\ \ SAR_{limit}} \leq 1$$

4. SAR Time Averaging Validation Test Procedures

Test Plan and test procedure for validating Samsung S.LSI TAS algorithm for FR1 scenarios.

4.1 Test sequence determination for validation

Two sequences for time varying Tx power are pre-defined as given below for FR1 case.

1. Test sequence A which is generated with one or two levels where one of the levels is maximum power level (Pmax) which is applied at least for 100s. Based on the second level this test sequence is sub-categorized into four different sequences used
   a. Test Sequence A.i where after Pmax, a second level of Plimit is requested till the end of the test
   b. Test Sequence A.ii where after Pmax, a second level of Pmax-3dB is requested till the end of the test
   c. Test Sequence A.iii where after Pmax, a second level of Plimit-3dB is requested till the end of the test

d. Test Sequence A.iv where only Pmax is requested till the end of the test

2. Test Sequence B is generated at multiple power levels that are specified in the Appendix as a function of Pmax and Plimit.

4.2. Test configuration selection for Validation TAS

This section provides general guidance for selecting test cases in TAS algorithm validation.

4.2.1 Test configuration selection for time-varying Tx power transmission

The Samsung S.LSI TAS algorithm is independent of band, modes or channel of any technology. Hence, we can validate using one or two combinations of band/mode/channel per technology. The criteria for selecting these would be based on the relative value of Plimit and Pmax as determined in SAR Char Report. Essentially, we need to pick this combination such that Plimit is less than Pmax so that the TAS algorithm will enforce power restriction.

4.2.2 Test configuration selection for change in call

The criteria to select the technology/band for transition between call setup and call drop is to choose the one with least Plimit among all bands. The test is performed with DUT requested power at Pmax so that the Samsung S.LSI TAS feature enforces power restriction for longest duration. The call change is performed when the DUT is operating with restricted power. One such test is sufficient since behavior is not dependent on band/technology.

4.2.3 Test configuration for change in technology/band

FCC specifies different measurement durations for time averaging based on operating frequency. The change of operating frequency can result in change of time window for averaging, for e.g. change from 100s averaging for frequency below 3GHz to 60s averaging for frequency above 3GHz in FR1. The criteria for selecting test case to demonstrate compliance across time window change is to pick a technology/band corresponding to each time window such that Plimit is less than Pmax. However, to show the performance of the TAS algorithm in this document, the case of low Plimit is considered, which is shown in SAR Char Report.

4.2.4 Test configuration for change in RSI (radio SAR index)

The criteria for selecting test case to demonstrate compliance across RSI change within a radio. The two RSI states are chosen by pick a technology/band from SAR Char. Report such that Plimit is less than Pmax for both states. However, to show the performance of the TAS algorithm in this document, the case of low Plimit is considered, which is shown in Table 7.2.1.

4.2.5 Test configuration for SAR exposure switching

The criteria for selecting test case is to pick an LTE band and a NR band with Plimit lower than Pmax in each case. The test is performed with both RATs connected in an EN-DC scenario. In the first portion of the test, DUT is requested to transmit at maximum power for NR and minimum power for LTE. In the second portion of the test, DUT is requested to transmit at maximum power for both NR and LTE. In the final portion of the test, DUT is requested to transmit at minimum power for NR and maximum power for LTE.

4.2.6 Test configuration for WCDMA time-varying Tx power

The criteria of selecting this test configuration is to demonstrate that Samsung S.LSI algorithm is independent on bands or technology used. We will show that the algorithm can control the transmitted power of a WCDMA transmission with varying requested power as in the LTE and NR technologies.

4.2.7 Test configuration for 2G time-varying Tx power

The criteria of selecting this test configuration is to demonstrate that Samsung S.LSI algorithm is independent on bands or technology used. We will show that the algorithm can control the transmitted power of a 2G transmission with varying requested power as in the LTE and NR technologies.

4.2.8 Test configuration for Spatial TAS

The criteria of selecting these tests configuration is to demonstrate the compliance of the TAS algorithm while transmitting on multiple antennas with a coupling factor of 0. This spatial TAS

algorithm will show that we can achieve enhanced performance based on the antenna coupling while ensuring compliance with FCC target level.

4.3 Test procedures for conducted power measurements

This section provides general conducted power measurement procedures to perform compliance test under dynamic scenarios.

4.3.1 Time-varying Tx power transmission scenario

This test is performed with two pre-defined test sequences as described in Section 4.1 for all technologies operating on sub-6GHz applying to both LTE and NR. The purpose of the test is to demonstrate the maximum power limiting enforcement and that the time-averaged SAR does not exceed the FCC limit at all times.

4.3.1.1 Test procedure

1. Using the Pmax and Plimit obtained in Table 7.2.1, generate the test sequence of power levels for each selected technology/band. Both test sequences A and B are generated. Maximum power can be changed according to DUT test results.
2. Establish the connection of the DUT to the call box in the selected RAT, with the call box requesting the DUT Tx power to be according to the sequence determined in Step 1. An initial value of Tx power will be set to 0dBm for 100s before the desired test sequence starts to help with post-processing of the time-average value with the very first value in the sequence. This is illustrated in the figure below

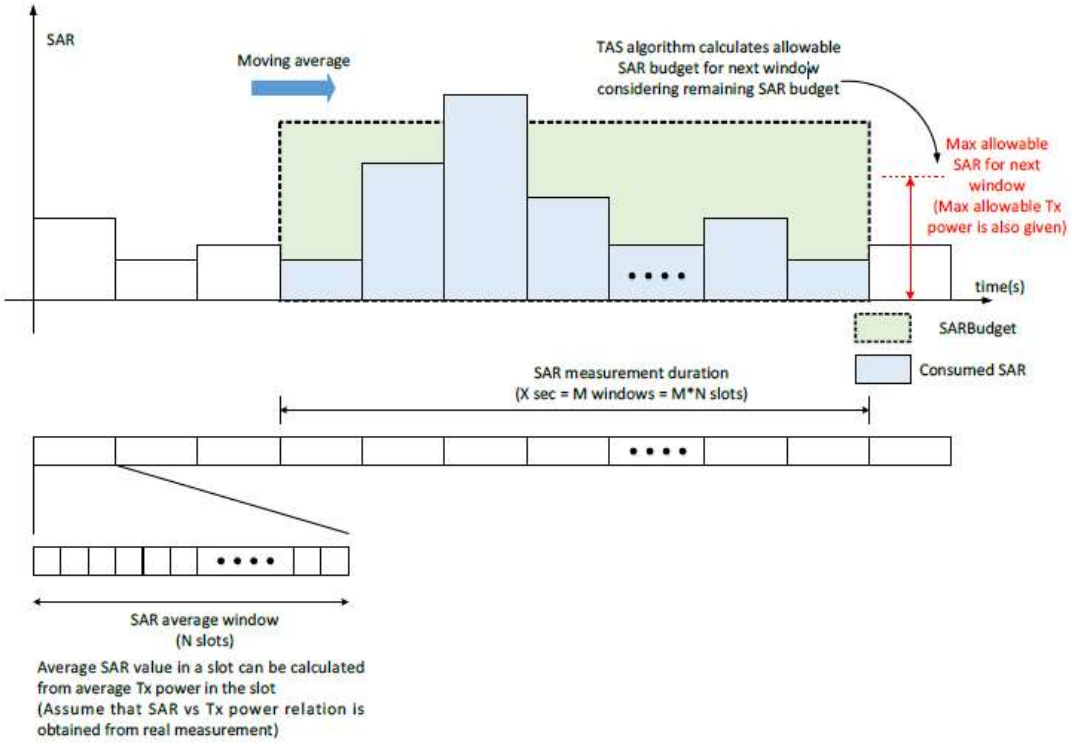

Figure 4.3-1 SAR measurement from Tx power using block-wise processing

3. Release connection.
4. After the completion of the test, prepare one plot with the following information:
   A. Instantaneous Tx power versus time measured in Step 2
   B. Requested Tx power versus time used in Step 2
   C. Time-averaged power over 100s using instantaneous values from Step 2
   D. Power level Plimit which is determined as meeting SAR target in Table 7.2.1(Pmax Plimit Table)
5. Make a second plot containing the following information:
   A. Computed time-averaged 1gSAR versus time determined in Step 2
   B. b. FCC 1gSAR limit of 1.6W/kg

The pass condition is to demonstrate time-averaged 1gSAR versus time shown in Step 5 value versus time does not exceed the FCC limit of 1.6 W/kg throughout the test duration. We would also demonstrate that time-averaged power does not exceed the Plimit at any time in the plot in Step 4.

4.3.2 Change in call scenario

This test is to demonstrate that Samsung S.LSI TAS feature correctly accounts for past Tx powers during time averaging when a new call is established. The call change has to be carried out when the power limit
enforcement is ongoing.

4.3.2.1 Test procedure

1. Establish radio connection of DUT with call box e.g. using LTE technology
2. Configure call box to set DUT Tx power to a low value of -10dBm for 100s.
3. Configure call box to send "ALL UP" power control commands and continue LTE transmission from DUT so that maximum power of Pmax is achieved.
4. After 60s of transmission at Pmax power level, release the call from call box.
5. After 10s, re-establish the LTE connection from call box to DUT and repeat sending "ALL UP" power control command to bring the Tx power to Pmax level again and continue till the end of the test.
6. Release LTE connection.
7. After the completion of the test, prepare one plot with the following information (a) Instantaneous Tx power versus time (b) Requested Tx power versus time (c) Time-averaged power over 100s using instantaneous values and (d) Power level Plimit which is determined as meeting SAR target
8. Make a second plot containing the following information (a) Computed time-averaged 1gSAR versus time and (b) FCC 1gSAR limit of 1.6W/kg.

Pass condition is to demonstrate time-averaged 1gSAR value versus time does not exceed the FCC limit of 1.6 W/kg throughout the test duration. It is required to check if SAR calculation is accounting for call drop and connection. Current TAS algorithm software makes the UE estimate the exact amount of Tx power and average SAR even during call drop and call re-establishment event. The UE stores time information when it goes into a sleep mode and wake-up to calculate Tx power on / off duration.

4.3.3 Change in technology/band

This test is to demonstrate that Samsung S.LSI TAS feature can properly handle change of technology/band and consequently time window as necessary during handover scenarios. Since both Plimit and window duration can change across bands, we have to use separate equations below for converting Tx power to SAR as well as apply some combined SAR exposure criteria as shown below.

$$SAR_1(t) = \frac{TxPower_1(t)}{P_{limit,1,FR1}} * SAR\_design\_target_1 \quad (4.3\text{-}1)$$

$$SAR_2(t) = \frac{TxPower_2(t)}{P_{limit,2,FR1}} * SAR\_design\_target_2 \quad (4.3\text{-}2)$$

where $P_{limit,1,FR1}$ would correspond to measured power at which first technology/band meets measured SAR level of $SAR\_design\_target_1$ as described in Table 7.2.1 with time-averaging duration of $T_{1,SAR}$. Similarly, the quantities $P_{limit,2,FR1}$, $SAR\_design\_target_2$, $T_{2,SAR}$ are defined for the second technology/band. When first band is chosen below 3GHz, we would have $T_{1,SAR}$ = 100s, and by choosing second band to be above 3GHz, we would use $T_{2,SAR}$ = 60s. On the other hand, when first band is chosen above 3GHz and second band below 3GHz, we would use $T_{1,SAR}$ = 60s and $T_{1,SAR}$ = 100s.

4.3.4 Test procedure for handover between two TAS RATs

1. Establish radio connection of DUT with call box e.g. using 5G FR1 NR technology
2. Configure call box to set DUT Tx power to a low value of 0dBm for 100s.
3. Configure call box to send "ALL UP" power control commands and continue NR transmission from DUT so that maximum power of Pmax is achieved. Continue transmission at the maximum power for 410s.
4. Change RAT from NR to LTE and configure call box to send "ALL UP" power control commands in LTE
5. Continue call in LTE at maximum power for 400s.
6. Release LTE connection
7. After the completion of the test, prepare one plot with the following information for each RAT (a)Instantaneous Tx power versus time (b) Time-averaged power for each RAT according to the averaging duration and (c) Plimit corresponding to each RAT
8. Make a second plot containing the following information (a) Computed time-averaged 1gSAR versus time for each RAT (b) Sum of time-averaged SAR computed according to Eqn (**4.3-1**) and (**4.3-2**), and (c) FCC1g SAR limit of 1.6W/kg

Pass condition is to demonstrate total time-averaged 1gSAR value versus time does not exceed the FCC limit of 1.6 W/kg throughout the test duration. It is required to check if power limiting enforcement is operated as expected when RAT change occurs in-between.

4.3.5 SAR exposure switching

This test is to demonstrate that Samsung S.LSI TAS feature can properly handle change of dominant SAR exposure radio in the case of two simultaneous active RATs. It involves changing the required power of both radios such that either one or both of the RATs becomes dominant contributor to total exposure ratio at different times of the test.

4.3.5.1 Test procedure for SAR exposure switching

1. Establish LTE and NR radio connection in NSA case with both call boxes, e.g. LTE and NR FR1 Technology.
2. Configure the LTE call box to send "ALL DOWN" power control commands for LTE and configure the NR call box to send "ALL UP" power control commands. This would correspond to NR dominant SAR scenario and continue this stage for about 220s.
3. In the second part of test, configure the LTE call box to send "ALL UP" power control commands and all transmissions are continued, resulting in maximum power requested from DUT for both LTE and NR. This stage of test is continued for another 110s.
4. In the third part of test, configure the NR call box to send "ALL DOWN" power control commands so that LTE becomes the dominant SAR radio. This stage is continued for another 110s.
5. Finally, both LTE and NR connections are released.

4.3.6 Change in RSI

This test is to demonstrate that Samsung S.LSI TAS feature can properly handle change of RSI resulting from different SAR index state detected by host platform software. It involves changing the Plimit value during the test for the same technology to emulate RSI change, while the SAR_design_target remains the same.

Note that the DUT has a proximity sensor to manage extremity exposure, which is represented using RSI = 0, the DUT has a Hotspot mode to manage body exposure which is represented using RSI = 2, which is represented using RSI = 1, the head exposure can be distinguished through audio receiver mode.

4.3.6.1 Test procedure for change in RSI

1. Establish radio connection of DUT with call box e.g. using NR SA FR1
2. Configure DUT to send at low Tx power of 0 dBm for 110s and set the RSI index corresponding to Plimit of 18dBm
3. Configure call box to send "ALL UP" power control commands and continue SA FR 1 transmission from DUT so that maximum power of Pmax is achieved. Continue the transmission for 200s.
4. Change the RSI index corresponding to lower value of 16dBm and continue the transmission for another 300s
5. Release the SA FR1 connection.

Pass condition is to demonstrate time-averaged 1gSAR value versus time does not exceed the FCC limit 1.6 W/kg throughout the test duration. It is required to check if power limiting enforcement is operated as expected when RSI index is changed during the test. Test Configurations.

4.3.7 Test procedure for handover from TAS RAT to a RAT operating in non-TAS mode

1. Establish radio connection of DUT with call box e.g. using LTE in Band B2
2. Configure call box to set DUT Tx power to a low value of 0dBm for 110s.
3. Configure call box to send "ALL UP" power control commands and continue LTE transmission from DUT so that maximum power of Pmax is achieved. Continue transmission at the maximum power for 120s.
4. Change RAT from LTE to WCDMA in Band B2 while disabling TAS and configure call box to send "ALL UP" power control commands in WCDMA
5. Continue call in WCDMA at maximum power for 400s. © SAMSUNG Electronics Co., Ltd. Confidential & Proprietary 36 Confidential
6. Release WCDMA connection

7. After the completion of the test, prepare one plot with the following information for each RAT (a) Instantaneous Tx power versus time (b) Time-averaged power for each RAT according to the averaging duration and (c) Plimit corresponding to each RAT 8. Make a second plot containing the following information (a) Computed time-averaged 1gSAR versus time for each RAT (b) Sum of time-averaged SAR computed according to Eqn. (6.3-1) and (6.3-2),and (c) FCC 1gSAR limit of 1.6W/kg

Pass condition is to demonstrate total time-averaged 1gSAR value versus time does not exceed the FCC limit of 1.6 W/kg throughout the test duration. It is required to check if power limiting enforcement is operated as expected when RAT change occurs in-between.

4.3.8 WCDMA time-varying Tx power

The test is to demonstrate that Samsung S.LSI TAS feature can properly handle the SAR exposure for WCDMA with varying requested power over time.

4.3.8.1 Test Procedure for WCDMA_Time_varying_Tx_power_Case1

1. Establish WCDMA connection of DUT with call box

2. Configure call box to set DUT Tx power to a low value of 0dBm for 100s.

3. Configure call box to send "ALL UP" power control commands and continue WCDMA transmission for 80s from DUT so that maximum power of Pmax is achieved.

4. Configure call box to set DUT Tx power to a lower value of Plimit(dBm)-3dB for 420s

5. Release WCDMA connection.

4.3.8.2 Test Procedure for WCDMA_Time_varying_Tx_power_Case2

1. Establish WCDMA connection of DUT with call box

2. Configure call box to set DUT Tx power to a low value of 0dBm for 100s.

3. Configure call box with requesting the DUT Tx power to be according to the sequence B generated and continue 2G transmission till the end of the test.

4. Release WCDMA connection

4.3.9 2G time-varying Tx power

The test is to demonstrate that Samsung S.LSI TAS feature can properly handle the SAR exposure for 2G with varying requested power over time.

4.3.9.1 Test Procedure for 2G_Time_varying_Tx_power_Case1

1. Establish 2G connection of DUT with call box

2. Configure call box to set DUT Tx power to a low value of 0dBm for 100s.

3. Configure call box to send "ALL UP" power control commands and continue 2G transmission for 500s from DUT so that maximum power of Pmax is achieved.

4. Release 2G connection.

4.3.9.2 Test Procedure for 2G_Time_varying_Tx_power_Case2

1. Establish 2G connection of DUT with call box

2. Configure call box to set DUT Tx power to a low value of 0dBm for 100s.

3. Configure call box with requesting the DUT Tx power to be according to the sequence B generated and continue 2G transmission till the end of the test.

4. Release 2G connection.

4.4 Spatial TAS

For the test cases with spatial TAS, we will consider 3 antennas (Main 1, Main 2 and Sub 2) with two antenna groups where each antenna group consists of two antennas and multiple bands as in Table 4-1.

Table 4-1 Antennas and bands used in the spatial TAS conducted tests

AG#	Antenna	Band
AG0	Main 1, 2	LTE 26, LTE 66, NR n41
AG1	Sub 2	NR n77

The coupling matrix considered during the tests is

$$R = \begin{bmatrix} 1 & 0 \\ 0 & 1 \end{bmatrix}$$

4.4.1 Test procedure for SA FR1 Antenna switching with spatial TAS

1. Establish radio connection of DUT with call box e.g. using NR FR1 technology (AG0)

2. Configure call box to set DUT Tx power to a low value of -10dBm for 140s.

3. Configure call box to send "ALL UP" power control commands and continue NR FR1transmission from DUT so that maximum power of Pmax is achieved for 140s.

4. Change the band from AG0 to AG1 so that the transmitting antenna changes to AG1 and continue transmission for 140s.

5. Change the band from Band AG1 to AG0 so that the transmitting antenna changes to AG0 and continue transmission till the end of the test.

4.4.2 Test procedure for NSA with spatial TAS

1. Establish LTE and NR radio connection in NSA case with both call boxes, e.g. LTE (AG0) and NR (AG1)

2. Configure the LTE call box to send "ALL Down" power control commands for LTE and configure the NR call box to send "ALL Down" power control commands and continue for 150s.

3. Configure the LTE call box to send "ALL Up" power control commands for LTE while keeping

the configuration of the NR call box at "ALL Down" power control commands. This would correspond to LTE dominant SAR scenario and continue this stage for about 140s.

4. Configure the NR call box to send "ALL UP" power control commands and all transmissions are continued, resulting in maximum power requested from DUT for both LTE and NR. This stage of test is continued for another 140s.

5. Configure the LTE call box to send "ALL DOWN" power control commands so that NR becomes the dominant SAR radio and continue transmission till the end of the test.

6. Finally, both LTE and NR connections are released.

4.4.3 Test procedure for NSA antenna switching with spatial TAS

1. Establish LTE and NR radio connection in NSA case with both call boxes, e.g. LTE (AG0) and NR (AG0)

2. Configure the LTE call box to send "ALL Down" power control commands for LTE and configure the NR call box to send "ALL Down" power control commands and continue for 150s.

3. Configure the LTE call box to send "ALL Up" power control commands for LTE and configure the NR call box to send "ALL Down" power control commands. This would correspond to LTE dominant SAR scenario and continue this stage for about 200s.

4. Configure the NR call box to send "ALL UP" power control commands and all transmissions are continued, resulting in maximum power requested from DUT for both LTE and NR. This stage of test is continued for another 200s.

5. Change NR (AG1) so that NR transmitting antenna is switched to AG1 and continue transmission for 200s

6. Configure the LTE call box to send "ALL DOWN" power control commands so that NR becomes the dominant SAR radio and continue transmission till the end of the test.

7. Finally, both LTE and NR connections are released.

5. Test Configurations

Plim values in green indicate Plimit < Pmax			Plimit values in grey indicate Plimit > Pmax			
Plimit corresponding to 1 W/kg (1g) 2.5W/kg(10g) SAR_Design_target						Pmax
SAR Exposure Position			Head (RCV ON)	Body Phablet		Maximum Tune-up Output Power (Burst Average Power)
Averaging volume			1g	1g	10g	
seperation Distance			0 mm	10 mm	0 mm	
Mode	Band	Antenna	RSI = 1	RSI =0,2		
GSM/GPRS/EDGE	850	MAIN 1	31.4	27.2		28.5
GSM/GPRS/EDGE	1900	MAIN 2	32.0	20.5		26.5
UMTS	2	MAIN 2	30.0	20.0		23.0
UMTS	4	MAIN 2	32.4	20.0		23.0
UMTS	5	MAIN 1	31.2	26.0		24.0
LTE FDD	2	MAIN 2	30.5	20.0		23.0
LTE FDD	2	MAIN 3	26.4	20.0		23.0
LTE FDD	66(4)	MAIN 2	29.7	20.0		23.0
LTE FDD	66(4)	MAIN 3	28.2	20.0		23.0
LTE FDD	12(17)	MAIN 1	33.2	28.7		24.5
LTE FDD	26(5)	MAIN 1	32.2	26.1		24.5
LTE TDD PC3	41	MAIN 2	28.2	20.0		23.0
NR FDD	5	MAIN 1	32.6	27.1		24.5
NR FDD	66	MAIN 2	30.3	20.0		23.5
NR TDD	41 (SRS 0)	MAIN 2	17.0	17.0		23.5
NR TDD	41 (SRS 1)	Sub 1	12.0	12.0		16.0
NR TDD	41 (SRS 2)	MAIN 3	13.5	13.5		18.5
NR TDD	41 (SRS 3)	Sub 4	14.5	14.5		20.0
NR TDD	77	Sub 3	17.0	17.0		25.5

Note:

1. Radio SAR indicator (RSI) in the table above means the SAR test configuration of each mobile communication technology.
2. WLAN/BT mode are not controlled by The Samsung S.LSI proprietary TAS (Time Average SAR) algorithm.
2. Plimit and Tune up output power Pmax above table correspond to average power level accounting for duty cycle in the case of TDD Modulation schemes. (GSM, LTE TDD, NR TDD)
3. Maximum tune up output Power Pmax is used to configure DUT during RF tune up procedure. The maximum allowed output power is equal to Tune up power +1 dB device design uncertainty.
4. Compared with the Plimit (Tune up Powers) declared in each RSI by the manufacturer and the Plimit (calculation) calculated by the SAR measurement of each RSI, the lower power is applied to the DUT as the Plimit at each RSI configurations.
5. When Free (RSI=0) takes higher priority. The Priority for power reduction was given in the order of Free (RSI=0), RCV (RSI=1) and Hotspot (RSI=2).

6. Test Case List

6.1 Test case list for sub-6GHz transmissions

To validate TAS algorithm in various sub-6GHz conditions, the chosen TC (Test Case) list is defined as in Table **6.1-1**

Table 6.1-1 Sub-6GHz TAS validation test case list

No.	Test Scenario	Test case	Test configuration
F_TC01	Time-varying Tx power transmission	LTE_Time_Varying_Tx_Power_Case_1	LTE Band 41,66 Test Seq. A
F_TC02		SA_FR1_Time_Varying_Tx_Power_Case_1	NR Band n41, n66, n77 Test Seq. A
F_TC03		LTE_Time_Varying_Tx_Power_Case_2	LTE Band 41, 66 Test Seq. B
F_TC04		SA_FR1_Time_Varying_Tx_Power_Case_2	NR Band n41, n66, n77 Test Seq. B
F_TC05	Change in call	LTE_Call_Disconnect_Reestablishment	LTE Band 41, 66
F_TC06	Re-selection in call	SA_FR1_to_LTE_RAT_Re-selection	NR Band n66 to LTE Band 41 NR Band n41 to LTE Band 66
F_TC07	SAR exposure switch	NSA_FR1_Dominant_Power_Switching	LTE Band 26 and NR Band n41 LTE Band 26 and NR Band n66
F_TC08	Change in RSI	SA_FR1_RF_SAR_Index_Change	NR Band n41
F_TC14	TAS to nonTAS H.O. LTE_to_WCDMA_H.O.	TAS to nonTAS H.O. LTE_to_WCDMA_H.O.	LTE Band 41 and WCDMA Band 5 LTE Band 66 and WCDMA Band 5
F_TC19	WCDMA time varying Tx power	WCDMA_Time_varying_Tx_power_Case1	WCDMA Band 2
F_TC20		WCDMA_Time_varying_Tx_power_Case2	
F_TC21	2G time varying Tx power	2G_Time_varying_Tx_power_Case1	GSM1900
F_TC22		2G_Time_varying_Tx_power_Case2	
F_TC24	Antenna Switching with Spatial TAS	NR_Ant_switching_Spatial_TAS	NR Band n41, 77
F_TC25	NSA with Spatial TAS	NSA_Spatial_TAS	LTE Band 66 and NR Band 77
F_TC26	NSA antenna switching with Spatial TAS	NSA_Ant_switching_Spatial_TAS	LTE Band 26 and NR Band n41 and NR Band n77

7. Conducted Power Test Results for Sub-6 TAS validation

7.1 Measurement set-up

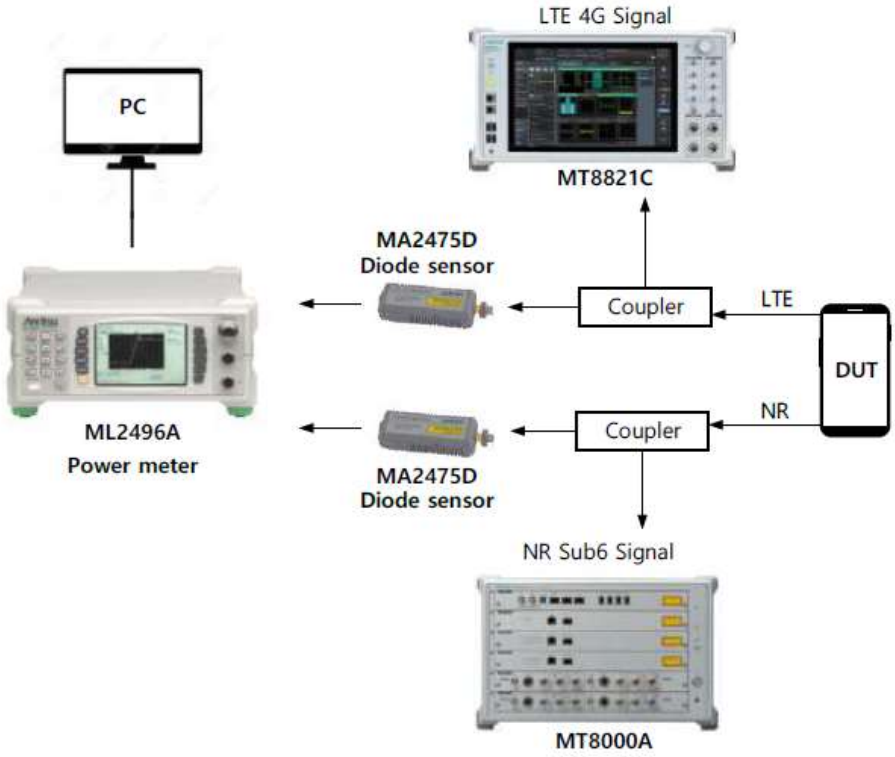

Figure 7.1-1 Test set-up for legacy and sub 6GHz

The test setup for TAS validation with sub-6GHz RATs only is shown in Figure 5.1-1. Normally, a power sensor would measure total power in the entire frequency of its specification e.g. 10MHz to 50GHz for the MA2475D unit. However, when two radios are active, we need to measure their powers separately for using the corresponding SAR mapping table. Therefore, this test setup considers scenarios where two radios would be transmitting from different ports of the DUT so that separate power sensors measure them individually. A common power meter is able to display and record the readings for each sensor at the same time for post processing at a PC. The signaling call boxes MT8000A and MT8821C are used to establish the call and data connection to the DUT on those same ports for NR and LTE, respectively.

The couplers are able to provide the transmit signal from DUT to power sensors while uplink and downlink signaling messages exchanged with the call boxes on the same paths. We can build

scripts to program a certain sequence of power control commands from the call boxes to the DUT which can essentially instruct the DUT to change its transmit power.

Thus, if we want DUT to transmit at maximum power in LTE, then continuous power up commands are sent by MT8821C. Similarly, continuous power up commands from MT8000A will try to increase NR power up to its maximum limit. Other power control scenarios which mimic real field behavior such as sequence of power up followed by power down are also possible as described in Section 4. All the path losses from RF port of DUT to the callbox and the power meters are calibrated and automatically entered as offsets in the callbox and power meter, which are also connected to the control PC used in the test setup. We use an Anritsu AMS tool, which is capable of executing the entire test sequence including requested power variation over time and call setup/disconnect scenarios based on pre-configured test case definition.

Power readings for each active technology are recorded every 100ms and dumped in an excel file.

A post processing tool is used to extract data from the excel file and plot the required metrics such as time-averaged

power, SAR values versus time as described in Section 4.

In summary, the tests have to be executed as following procedure.

1. Measure conduction sub 6GHz Tx power corresponds to SAR regulation.
2. Set sub 6GHz power level with some margin. And start the test
3. Execute time-varying test scenarios. And record sub 6GHz power using sub 6GHz power meter equipment.
4. Plot the recorded results over measurement time. And evaluate the results for validation.

Note that Plimit is different according to the used OEM, so it is necessary to set the Plimit suitable for each

terminal.

7.2 *Plimit* and *Pmax* measurement results

The measured *Plimit* for all the selected radio configurations are listed in Table 7.2.1. *Pmax* was also measured for radio configurations selected for testing time-varying Tx power transmission scenario in order to generate test sequences following the test procedures. Note that Table 7.2.1 is not actual Plimit corresponding to 1W/kg SAR, but our measured averaged power when forcing Plimit in our SW based on Table 7.2.1.

Test Case #	Test scenario	Tech	Band	Antenna	RSI	RB/offset/BW	Mode	Congfiguration	Plimit setting (dBm)	Pmax setting (dBm)	measured Plimit (dBm)	measured Pmax (dBm)
1-1	Time-varying Tx power transmission	LTE	66	Main2	2	1RB/0offset/20MHz	QPSK	1g/10mm/Hotspot	20.0	23.0	19.37	22.79
1-2												
2-1			41	Main2	2	1RB/0offset/20MHz	QPSK	1g/10mm/Hotspot	22.0	23.0	21.41	23.58
2-2												
3-1		SA/FR1	n66	Main2	2	1RB/53offset/20MHz	DFT-s QPSK	1g/10mm/Hotspot	20.0	23.5	20.16	23.24
3-2												
4-1			n41	Main2	2	1RB/1offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	23.5	16.33	23.71
4-2												
5-1			n77	Sub2	2	1RB/271offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	24.0	16.67	23.97
5-2												
6-1	Change in Call	LTE	66	Main2	2	1RB/0offset/20MHz	QPSK	1g/10mm/Hotspot	20.0	23.0	19.37	22.79
6-2			41	Main2	2	1RB/0offset/20MHz	QPSK	1g/10mm/Hotspot	22.0	23.0	21.41	23.58
7-1	Re-selection	SA/FR1	n66	Main2	2	1RB/53offset/20MHz	DFT-s QPSK	1g/10mm/Hotspot	20.0	23.5	20.16	23.24
		LTE	41	Main2	2	1RB/0offset/20MHz	QPSK		22.0	23.0	21.41	23.58
7-2		SA/FR1	n41	Main2	2	1RB/1offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	23.5	16.33	23.71
		LTE	66	Main2	2	1RB/0offset/20MHz	QPSK		20.0	23.0	19.37	22.79
8-1	SAR exposure Switch	NSA/FR1	n66	Main2	2	1RB/53offset/20MHz	DFT-s QPSK	1g/10mm/Hotspot	20.0	23.5	20.16	23.24
		LTE	26	Main1	2	1RB/0offset/15MHz	QPSK		24.5	24.5	24.22	24.22
8-2		NSA/FR1	n41	Main2	2	1RB/1offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	23.5	16.33	23.71
		LTE	26	Main1	2	1RB/0offset/15MHz	QPSK		24.5	24.5	24.22	24.22
9	RSI Change	SA/FR1	n66	Main2	2	1RB/53offset/20MHz	QPSK	1g/10mm/Hotspot	20.0	23.5	20.16	23.24
					1	1RB/53offset/20MHz		1g/0mm/RCV	23.5	23.5	23.24	23.24
10-1	TAS to Non TAS	LTE	66	Main 2	2	1RB/0offset/20MHz	QPSK	1g/10mm/Hotspot	20.0	23.0	19.37	22.79
		UMTS	5	Main 1	2	-	RMC		24.0	24.0	24.45	24.45
10-2		LTE	41	Main 2	2	1RB/0offset/20MHz	QPSK	1g/10mm/Hotspot	22.0	23.0	21.41	23.58
		UMTS	5	Main 1	2	-	RMC		24.0	24.0	24.45	24.45
11-1	WCDMA time varying Tx power	UMTS	2	Main 2	2	-	RMC	1g/10mm/Hotspot	20.0	23.0	19.38	22.80
11-2												
12-1	2G time varying Tx power	2G	GSM 1900	Main 2	2	-	2Tx	1g/10mm/Hotspot	20.5	23.0	21.28	23.51
12-2												

13	Antenna Switching with Spatial TAS	SA/FR1	n41	Main 2	2	1RB/1offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	23.5	16.33	23.71
			n77	Sub 2	2	1RB/271offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	24.0	16.67	23.97
14	NSA with Spatial TAS	LTE	66	Main 2	2	1RB/0offset/20MHz	QPSK	1g/10mm/Hotspot	20.0	23.0	19.37	22.79
		NSA/FR1	n77	Sub 2	2	1RB/271offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	24.0	16.67	23.97
15	NSA antenna switching with Spatial TAS	LTE	26	Main 1	2	1RB/0offset/15MHz	QPSK	1g/10mm/Hotspot	24.5	24.5	24.22	24.22
		NSA/FR1	n41	Main 2	2	1RB/1offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	23.5	16.33	23.71
		NSA/FR1	n77	Sub 2	2	1RB/271offset/100MHz	DFT-s QPSK	1g/10mm/Hotspot	17.0	24.0	16.67	23.97

Table 7.2.1.

* Plimit and Tune up output power Pmax in above table correspond to average power level after accounting for duty cycle
(Duty : 100%) in the case of TDD Modulation schemes (GSM, LTE TDD, NR TDD)

7.3 Time-varying Tx power measurement results

Following the test procedure in Section 4.3.1, the conducted Tx power measurement results for all selected test cases are listed in this section. In all conducted Tx power plots, the blue line shows the measured instantaneous power using the power meter, the red line shows the time-averaged Tx power and yellow line shows the Plimit value corresponding to measured value. In all SAR plots, the dotted blue line shows the time-averaged 1g SAR while the red line shows the corresponding FCC limit of 1.6W/kg. Time-varying Tx power measurements were conducted for TC01-04 in Table 6.1-1 by generating the test sequence A or B given in Appendix.

TC01: LTE_Time_Varying_Tx_Power_Case_1 [LTE B66]

Figure 7.3-1 Time average conducted power of LTE B66 in TC01

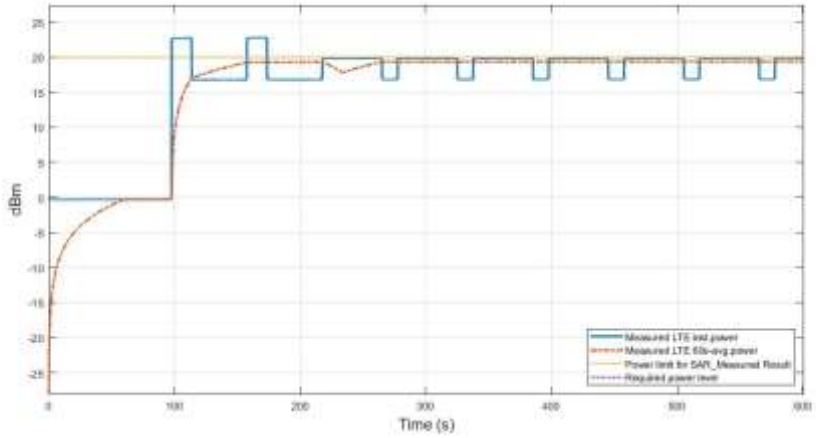

Figure 7.3-3 Time average conducted power of LTE B66 in TC01

Figure 7.3-1 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-1, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-2 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

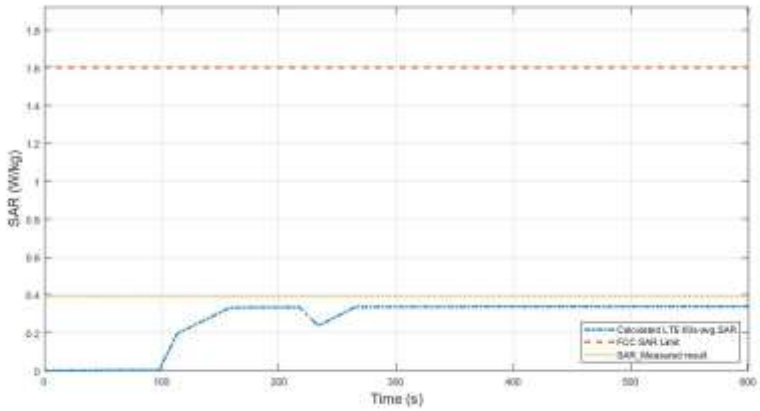

Figure 7.3-2 Total time-averaged SAR in TC01

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.339 W/kg
Device uncertainty	1 dB

TC01: LTE_Time_Varying_Tx_Power_Case_1 [LTE B41]

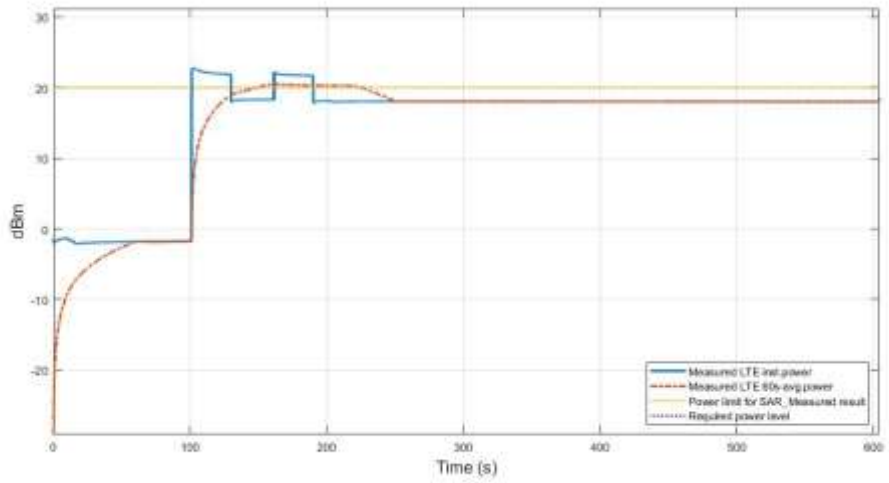

Figure 7.3-3 Time average conducted power of LTE B41 in TC01

Figure 7.3-3 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-3, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-4 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

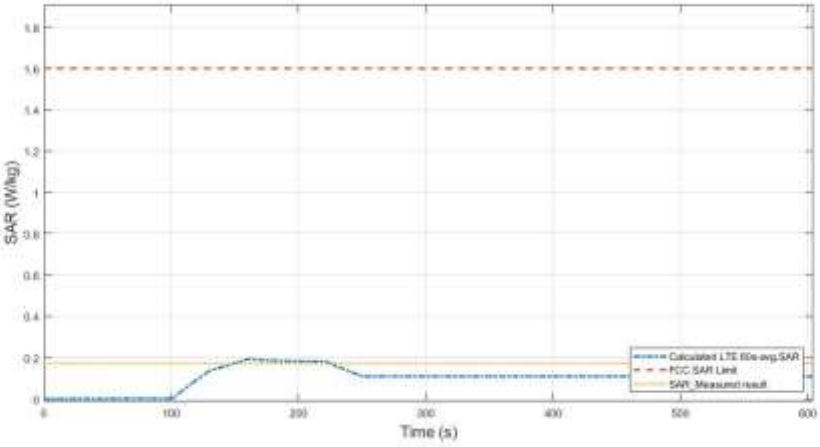

Figure 7.3-4 Total time-averaged SAR in TC01

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.195 W/kg
Device uncertainty	1 dB

TC02: SA_FR1_Time_Varying_Tx_Power_Case_1 [n66]

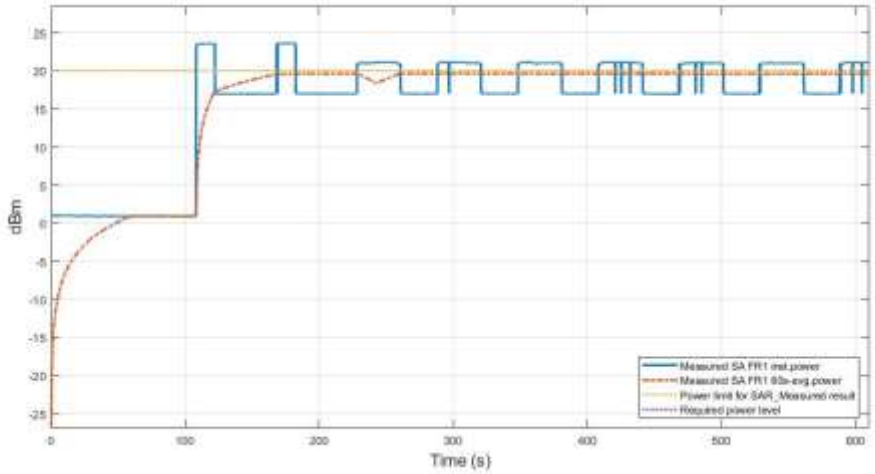

Figure 7.3-5 Time-average conducted power of SA FR1 n66 in TC02

Figure 7.3-5 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-5, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-6 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

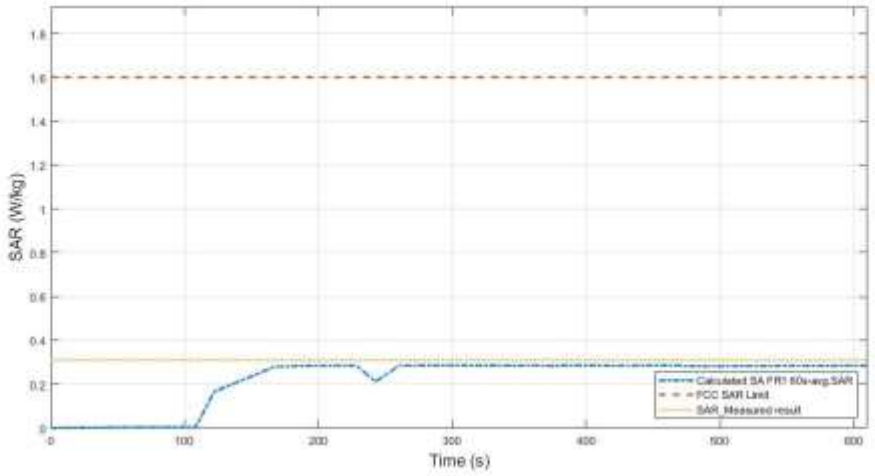

Figure 7.3-6 Total time-averaged SAR in TC02

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.286 W/kg
Device uncertainty	1 dB

TC02: SA_FR1_Time_Varying_Tx_Power_Case_1 [n41]

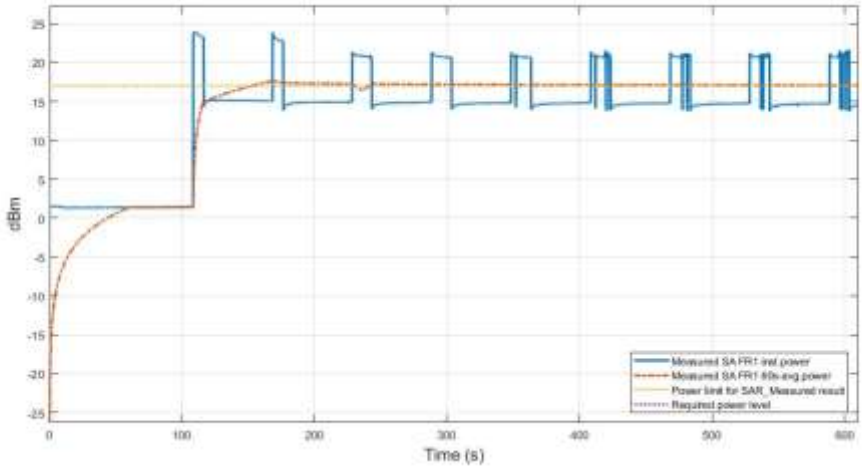

Figure 7.3-7 Time-average conducted power of SA FR1 n41 in TC02

Figure 7.3-7 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-7, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-8 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

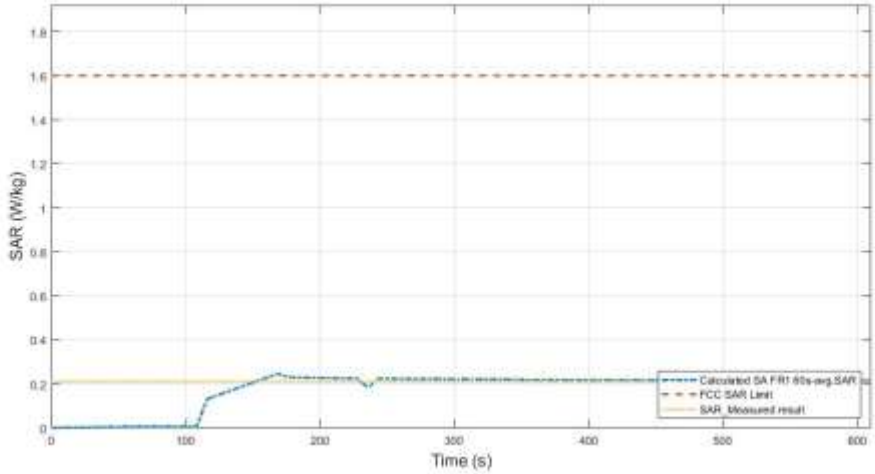

Figure 7.3-8 Total time-averaged SAR in TC02

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.246 W/kg
Device uncertainty	1 dB

TC02: SA_FR1_Time_Varying_Tx_Power_Case_1 [n77]

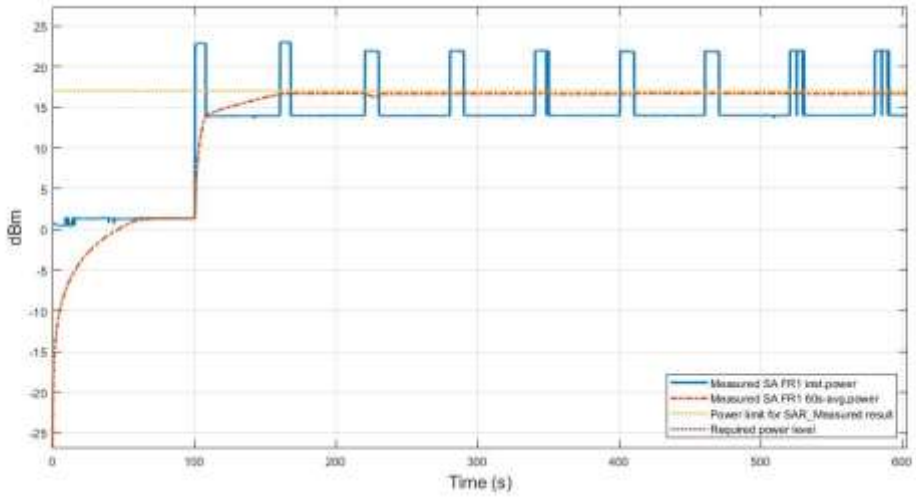

Figure 7.3-9 Time-average conducted power of SA FR1 n41 in TC02

Figure 7.3-9 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-9, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-10 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

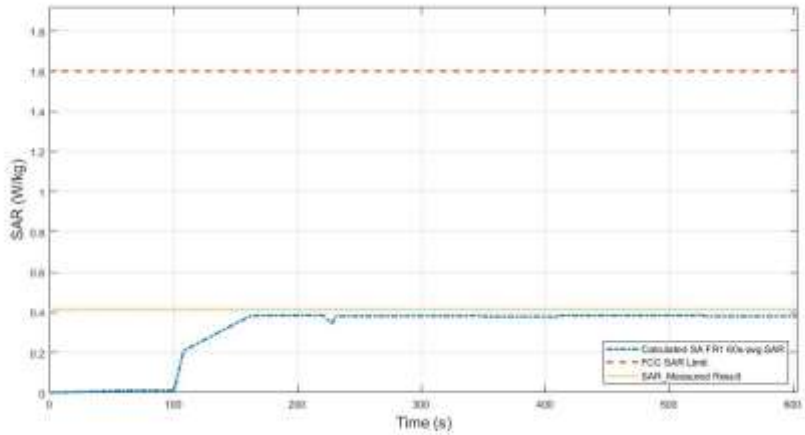

Figure 7.3-10 Total time-averaged SAR in TC02

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.387 W/kg
Device uncertainty	1 dB

TC03: LTE_Time_Varying_Tx_Power_Case_2 [LTE B66]

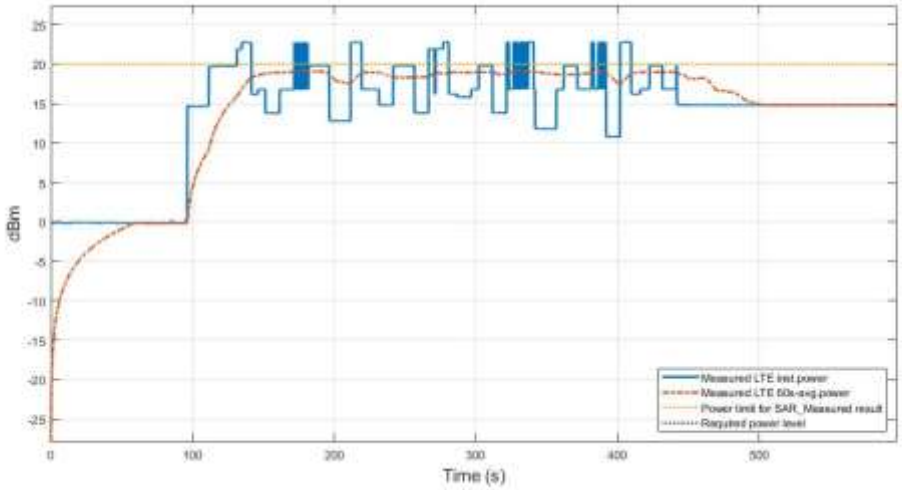

Figure 7.3-11 Conducted Tx power of LTE B66 in TC03

Figure 7.3-11 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-11, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-12 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

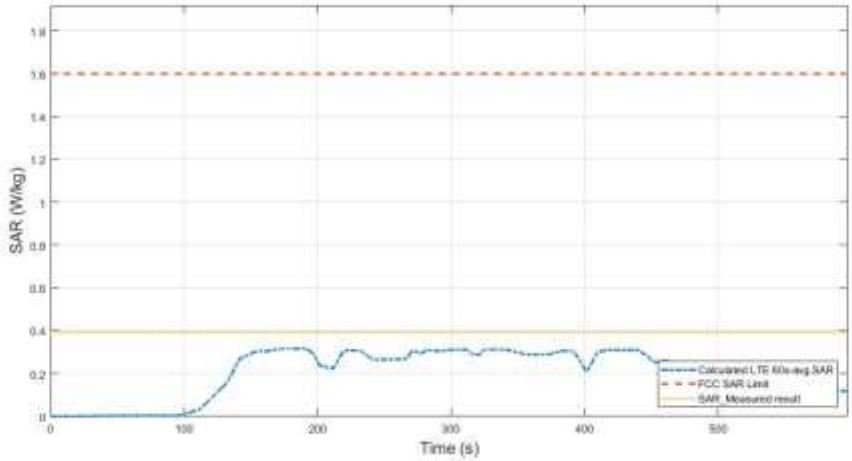

Figure 7.3-12 Total time-averaged SAR in TC03

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.317 W/kg
Device uncertainty	1 dB

TC03: LTE_Time_Varying_Tx_Power_Case_2 [LTE B41]

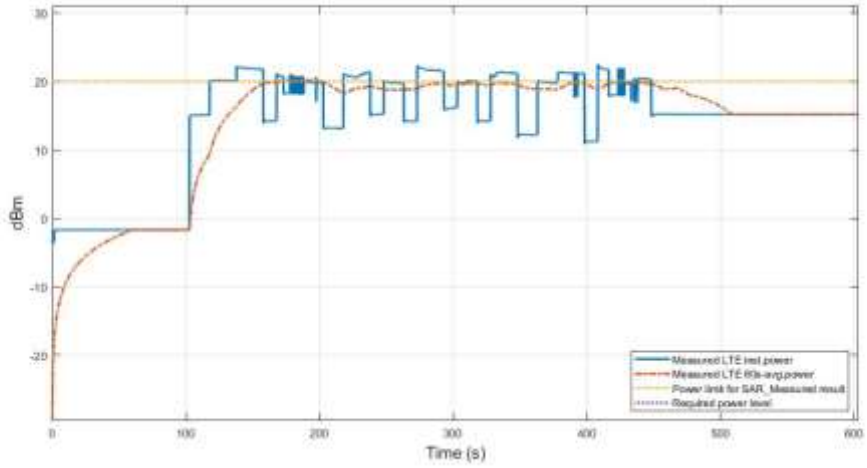

Figure 7.3-13 Conducted Tx power of LTE B41 in TC03

Figure 7.3-13 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-13, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-14 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

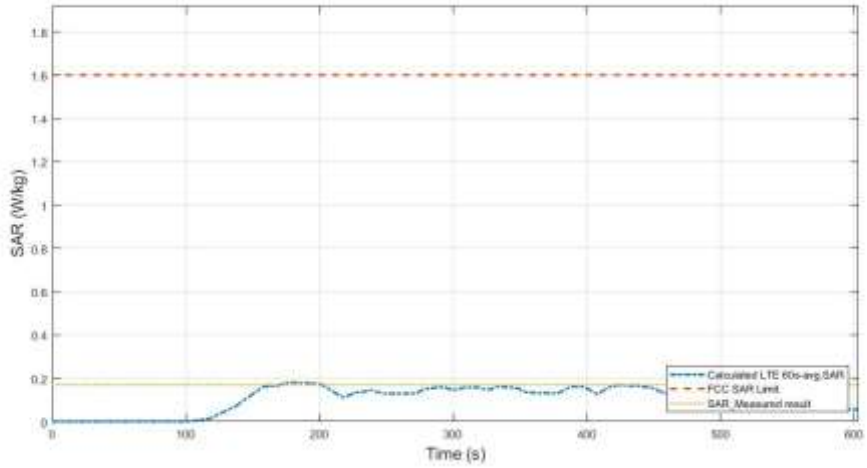

Figure 7.3-14 Total time-averaged SAR in TC03

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.181W/kg
Device uncertainty	1 dB

TC04: SA_FR1_Time_Varying_Tx_Power_Case_2 [n66]

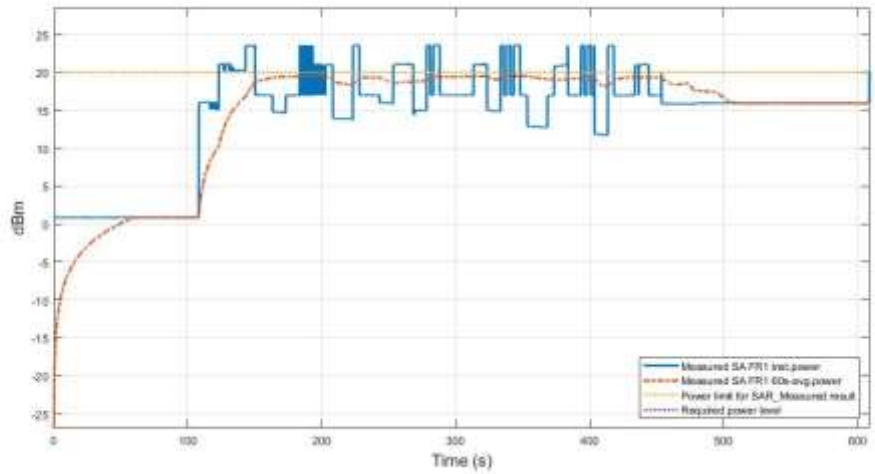

Figure 7.3-15 Conducted Tx power for SA FR1 n66 in TC04

Figure 7.3-15 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-15, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-16 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

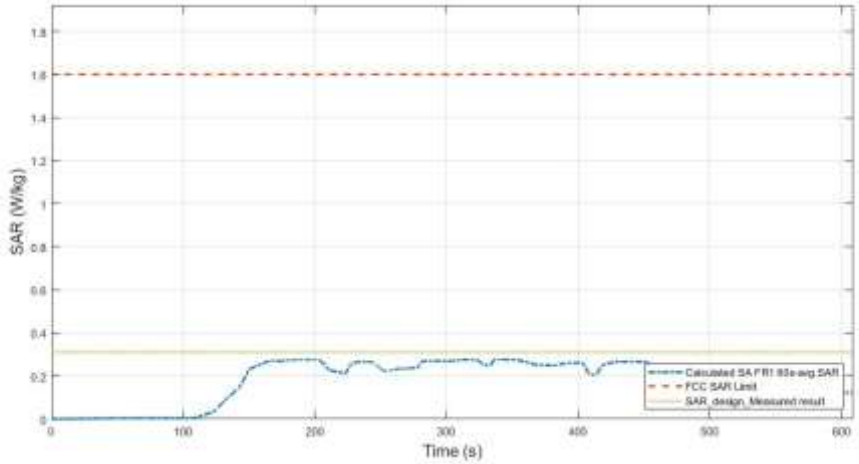

Figure 7.3-16 Total time-averaged SAR in TC04

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.277 W/kg
Device uncertainty	1 dB

TC04: SA_FR1_Time_Varying_Tx_Power_Case_2 [n41]

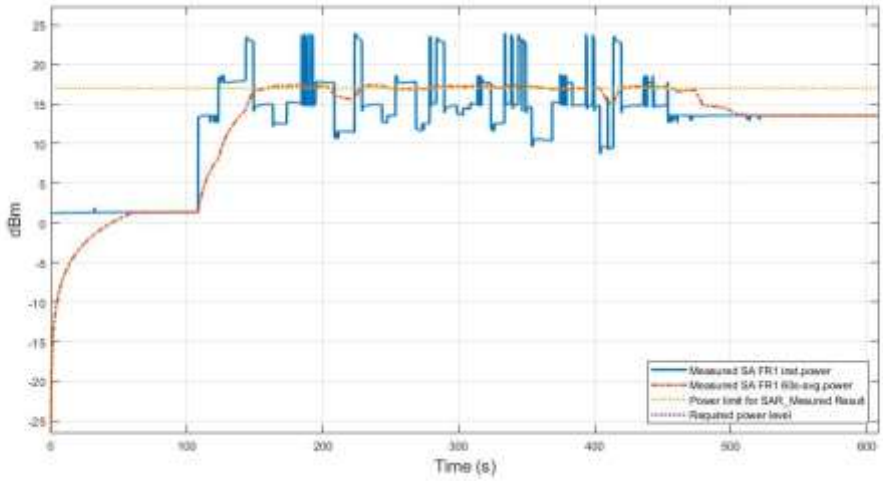

Figure 7.3-17 Conducted Tx power for SA FR1 n41 in TC04

Figure 7.3-17 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-17, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-18 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

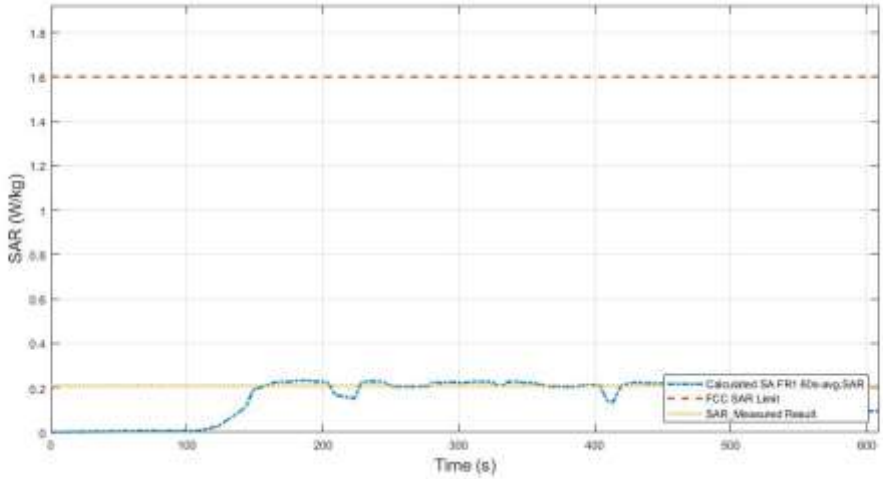

Figure 7.3-18 Total time-averaged SAR in TC04

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.235 W/kg
Device uncertainty	1 dB

TC04: SA_FR1_Time_Varying_Tx_Power_Case_2 [n77]

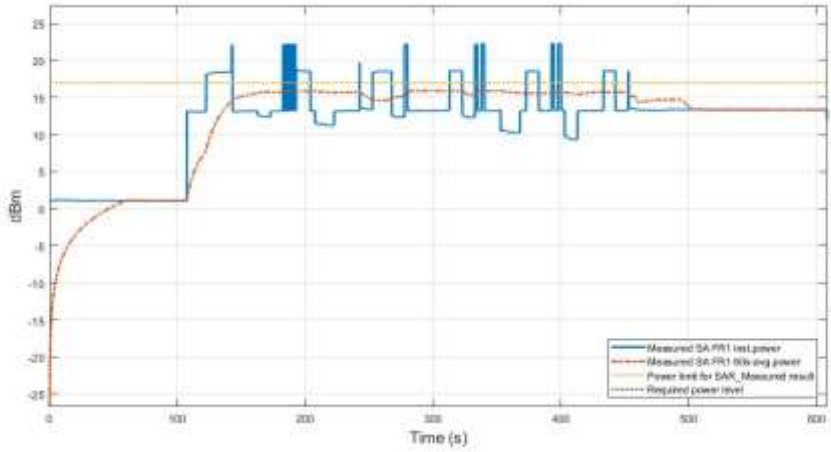

Figure 7.3-19 Conducted Tx power for SA FR1 n77 in TC04

Figure 7.3-19 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR measured value. The test result of this band got lower value than FCC 1g designed target 1.0W/kg. As shown in Figure 7.3-19, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-20 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg.

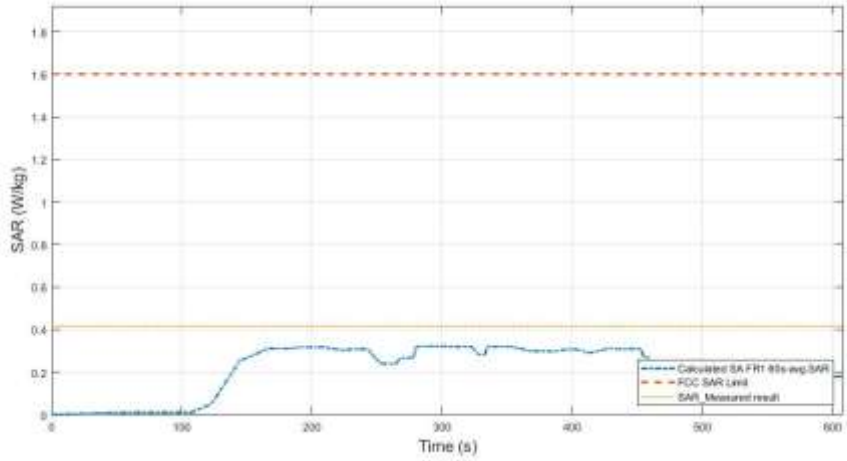

Figure 7.3-20 Total time-averaged SAR in TC04

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.322 W/kg
Device uncertainty	1 dB

7.4 Change in call test results

The test results in this section are obtained following the procedure in Section 4.3.2. The test case corresponds to TC05 in Table 6.1-1

TC05: LTE_Call_Disconnect_Reestablishment [LTE B66]

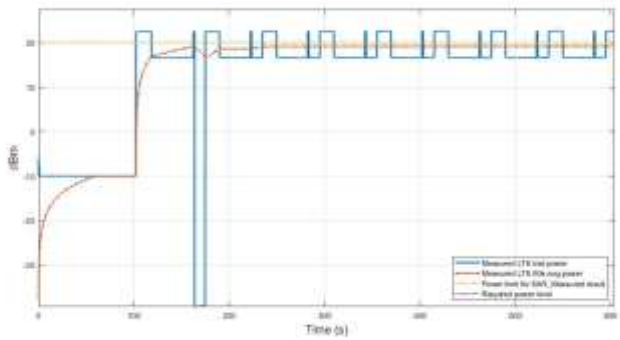

Figure 7.4-1 Conducted Tx power in Call_Disconnect_Reestablishment LTE Band 66 case in TC05

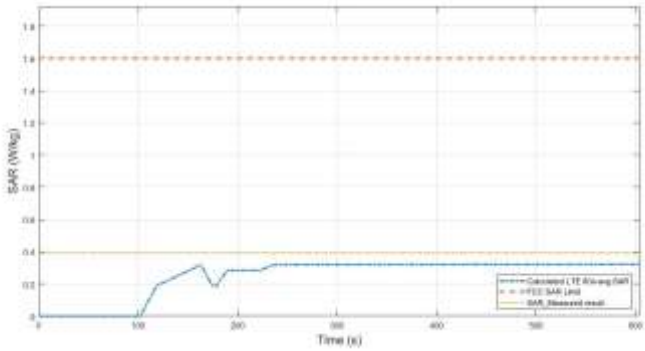

Figure 7.4-1 shows the instantaneous and time-averaged Tx power for this test. The call disconnected around 160s and resumed after 10s. It is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is lower than the value of Plimit. Figure 7.4-2 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg. Looking at the results, it can be seen that even if transmission is stopped due to a call drop, the SAR value measured for a period of time window is stored in the window section and is continuously checked.

Figure 7.4-2 Conducted Tx power in Call_Disconnect_Re-establishment LTE Band 66 case TC05

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.323 W/kg
Device uncertainty	1 dB

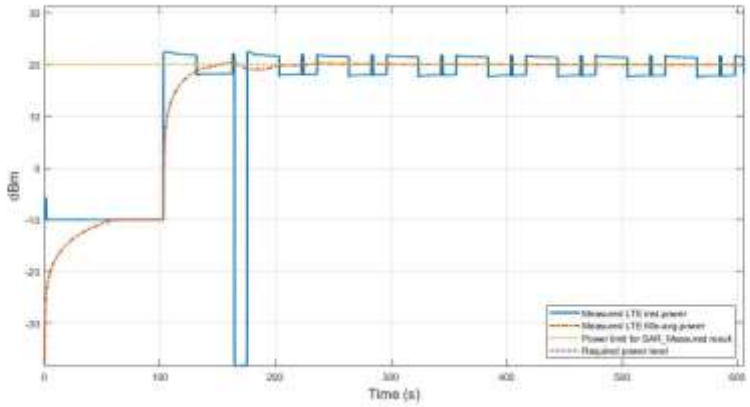

Figure 7.4-3 Conducted Tx power in Call_Disconnect_Re-establishment LTE Band 41 case in TC05

Figure 7.4-3 shows the instantaneous and time-averaged Tx power for this test. The call disconnected around 160s and resumed after 10s. It is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is lower than the value of Plimit. Figure 7.4-4 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/kg. Looking at the results, it can be seen that even if transmission is stopped due to a call drop, the SAR value measured for a period of time window is stored in the window section and is continuously checked.

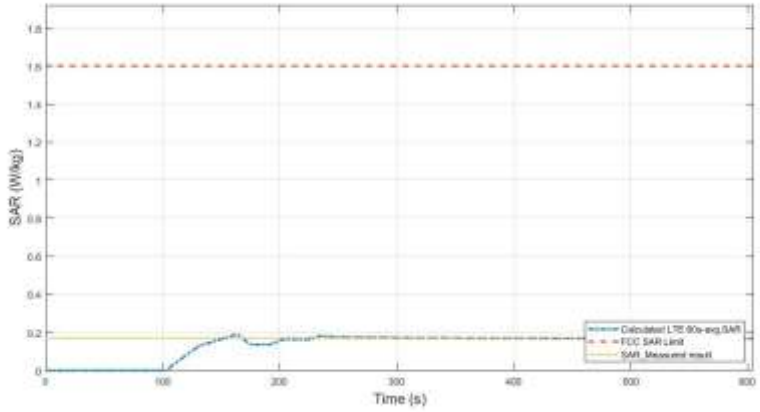

Figure 7.4-4 Conducted Tx power in Call_Disconnect_Re-establishment LTE Band 41 case TC05

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.190 W/kg
Device uncertainty	1 dB

7.5 Re-selection in call test results

The test results in this section are obtained following the procedure in Section 4.3.4. The test cases correspond to TC06 in Table 6.1-1

TC06: FR1 to LTE IRAT Re-selection

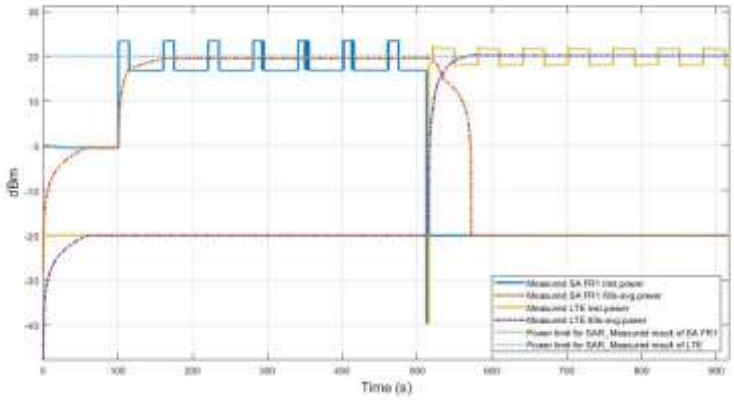

Figure 7.5-1 Conducted Tx power for SAR IRAT re-selection in test [n66 to LTE Band 41] in TC06

Figure 7.5-1 shows the instantaneous and time-averaged conducted Tx power for both LTE Band 41 and NR FR1 Band n66 for the duration of the test. Around time stamp of ~510s, a RAT re-selection from NR Band n66 to LTE Band 41 was executed, resulting in reduction of time-averaged power of Band n66 and simultaneous increase in time-averaged power of Band 41. Figure 7.5-2 shows the time-averaged 1gSAR value for each of LTE Band 41 and NR FR1 Band n66, as well as the total SAR value. We can see that the total 1gSAR is higher during the band transitions, but is always under the total FCC limit of 1.6W/kg.

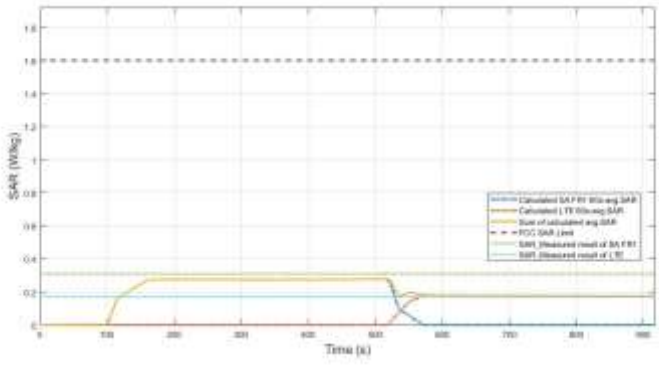

Figure 7.5-2 Conducted Tx power for SAR IRAT re-selection in test TC06

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (yellow curve)	0.280 W/kg
Device uncertainty	1 dB

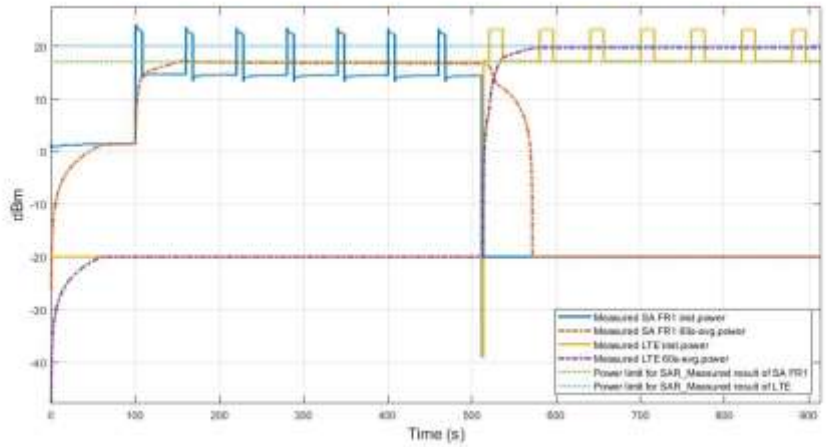

Figure 7.5-3 Conducted Tx power for SAR IRAT re-selection in test [n41 to LTE Band 66] in TC06

Figure 7.5-3 shows the instantaneous and time-averaged conducted Tx power for both LTE Band 66 and NR FR1 Band n41 for the duration of the test. Around time stamp of ~510s, a RAT re-selection from NR Band 41 to LTE Band 66 was executed, resulting in reduction of time-averaged power of Band n41 and simultaneous increase in time-averaged power of Band 66. Figure 7.5-4 shows the time-averaged 1gSAR value for each of LTE Band 66 and NR FR1 Band n41, as well as the total SAR value. We can see that the total 1gSAR is higher during the band transitions, but is always under the total FCC limit of 1.6W/kg.

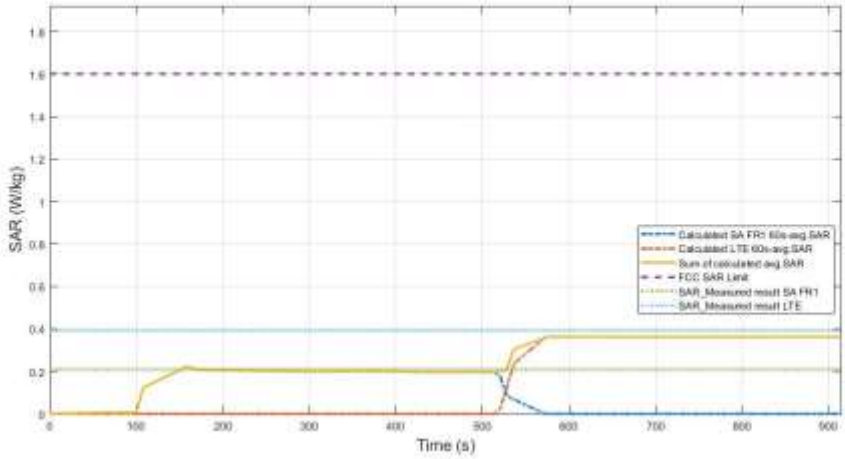

Figure 7.5-4 Conducted Tx power for SAR IRAT re-selection in test TC06

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (yellow curve)	0.363 W/kg
Device uncertainty	1 dB

7.6 Switch in SAR exposure test results

The test results in this section are obtained following the procedure in Section 4.3.5 The test cases correspond to TC07 in Table 6.1-1

TC07: NSA_FR1_Dominant_Power_Switching

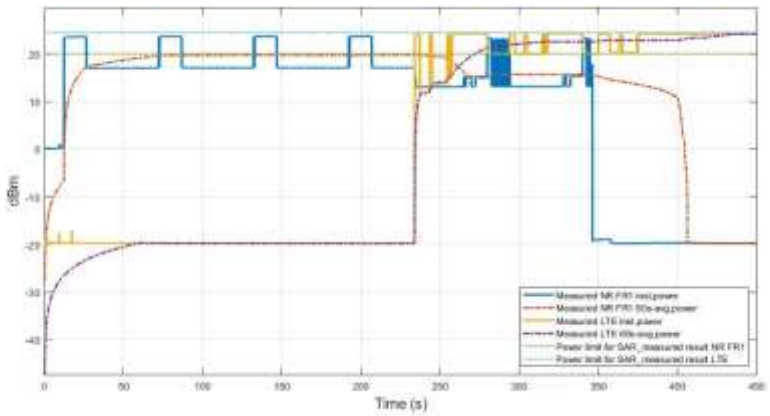

Figure 7.6-1 Time average SAR of LTE Band 26 and FR1 n66 EN-DC case in TC07

Figure 7.6-1 shows the instantaneous and time-averaged Tx power for both LTE band B25 and NR FR1 band n66 versus time. When both LTE and FR1 operate, the SAR value was the highest instantaneously, but it can be seen that sum of average power in LTE and FR1 decreases again as soon as it is turned off. Figure 7.6-2 shows the computed time-averaged SAR value for LTE and FR1 as well as the sum. This result was computed based on SAR measured result. It was confirmed that algorithm operated under the total SAR design target limit of 1W/kg, while also being under the FCC limit of 1.6W/kg at all times. After the operation of FR1 is turned off, it can also be seen that the average power of LTE increases.

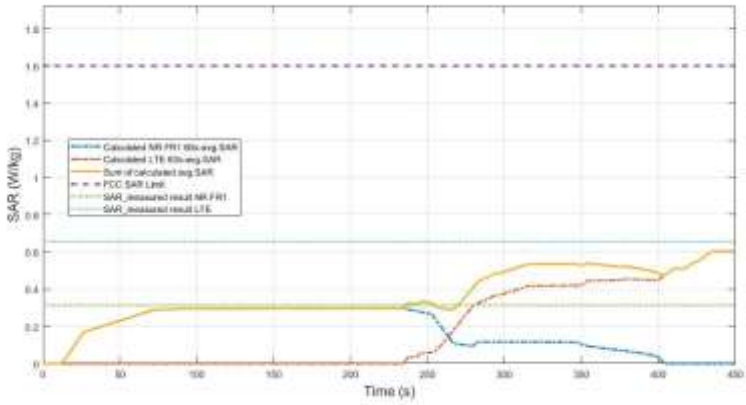

Figure 7.6-2 Total time-averaged SAR in TC07

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (yellow curve)	0.604 W/kg
Device uncertainty	1 dB

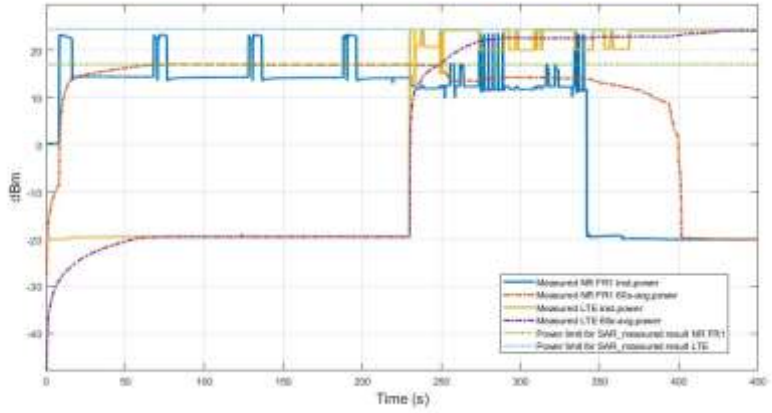

Figure 7.6-3 Time average SAR of LTE Band 26 and FR1 n41 EN-DC case in TC07

Figure 7.6-3 shows the instantaneous and time-averaged Tx power for both LTE band B26 and NR FR1 band n41 versus time. When both LTE and FR1 operate, the SAR value was the highest instantaneously, but it can be seen that sum of average power in LTE and FR1 decreases again as soon as it is turned off. Figure 7.6-4 shows the computed time-averaged SAR value for LTE and FR1 as well as the sum. This result was computed based on SAR measured result. It was confirmed that algorithm operated under the total SAR design target limit of 1W/kg, while also being under the FCC limit of 1.6W/kg at all times. After the operation of FR1 is turned off, it can also be seen that the average power of LTE increases.

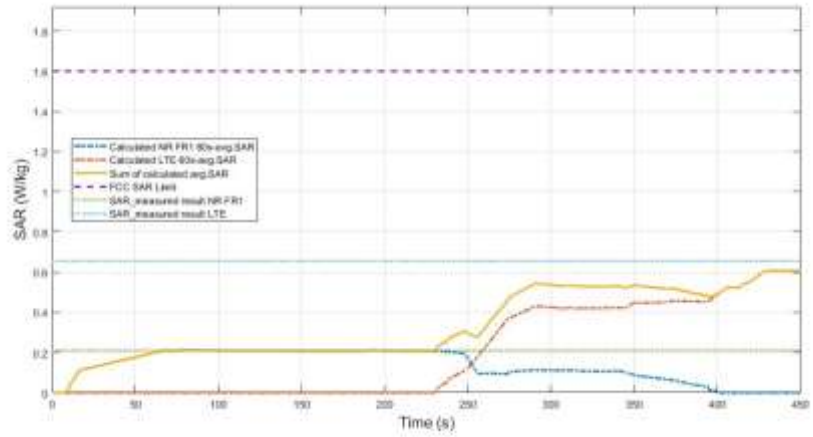

Figure 7.6-4 Total time-averaged SAR in TC07

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (yellow curve)	0.607 W/kg
Device uncertainty	1 dB

7.7 Change in RSI value results

The test results in this section are obtained following the procedure in Section 4.3.6. The test cases correspond to TC08 in Table 6.1-1

TC08: SA_FR1_RF_SAR_Index_Change

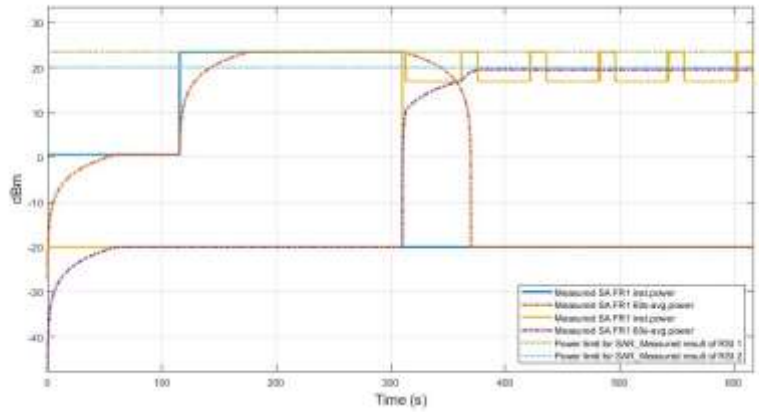

Figure 7.7-1 Conducted Tx power for SAR RSI Change FR1 n66 in TC08

Figure 7.7-1 shows the instantaneous and time-averaged conducted Tx power for both SA FR1 Band n66 for the duration of the test. Around time stamp of ~310s, the RSI value is changed from high RSI with Plimit of 23dBm to lower RSI with Plimit of 20 dBm, resulting in reduction of target time-averaged power of SA FR1 Band n66. Figure 7.7-2 shows the time-averaged 1gSAR value for each of low and high RSI value, as well as the total SAR value. We can see that the total 1gSAR is always under the total FCC limit of 1.6W/Kg.

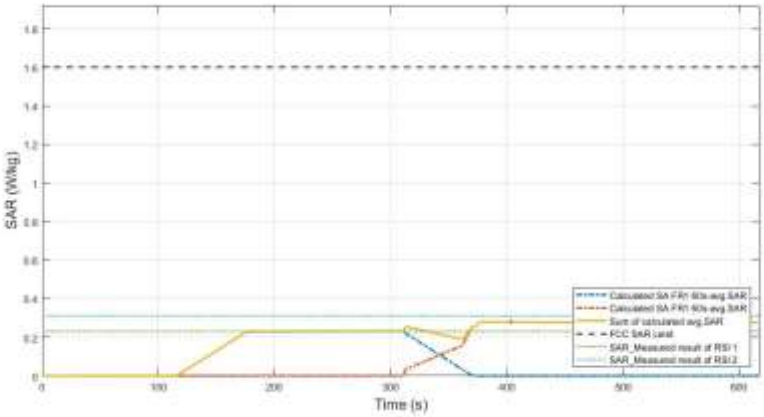

Figure 7.7-2 Total time-averaged SAR FR1 n77 in TC08

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (yellow curve)	0.280 W/kg
Device uncertainty	1 dB

7.8 TAS to non TAS H.O

The test results in this section are obtained following the procedure in Section 4.3.7. The test cases correspond to TC14 in Table 6.1-1

TC14: TAS to non TAS H.O

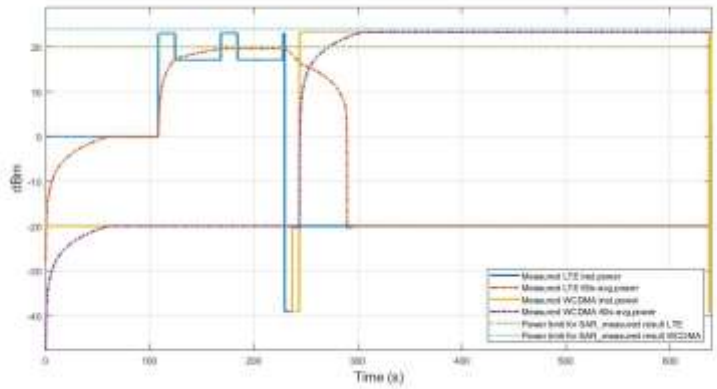

Figure 7.8-1 Conducted Transmitted Power of test [LTE Band 66 to UMTS Band 5] in TC14

Figure 7.8-1 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR FCC Limit value. The setting value and measured values are described in Table 7.2.1. At first, during 230s, LTE Band 66 transmitted. After 230s, the UMTS Band 5 transmitted for 400s. Both bands transmitted at maximum power throughout all intervals. However, for LTE Band 66, according to TAS algorithm, it operated under the SAR design Target 1.0W/kg. This result was computed that based on measured SAR result. Consequently, the average SAR in Figure 7.8-2 is under 1W/kg which is below the FCC limit of 1.6W/kg.

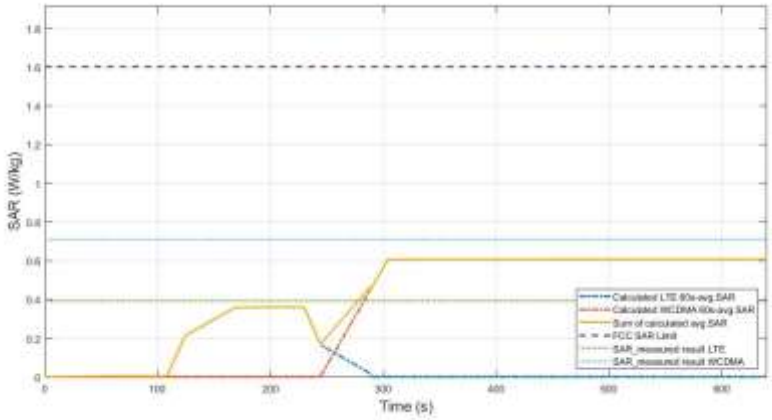

Figure 7.8-2 Total time-averaged SAR in TC14

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.607 W/kg
Device uncertainty	1 dB

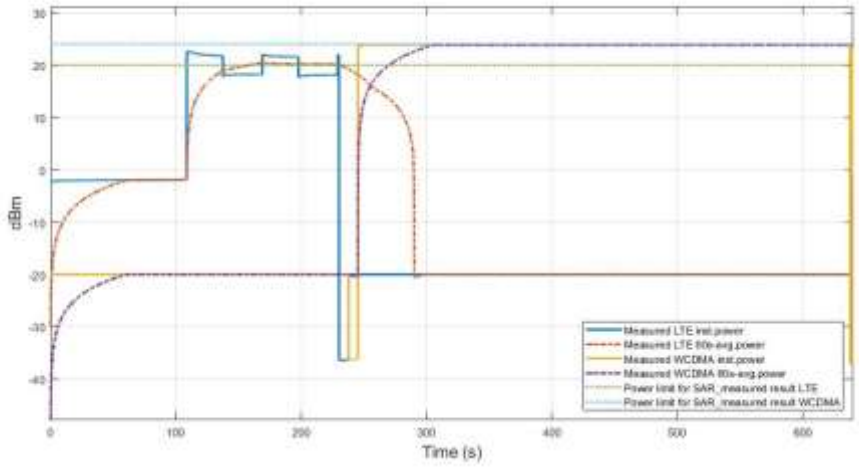

Figure 7.8-3 Conducted Transmitted Power of test [LTE Band 41 to UMTS Band 5] in TC14

Figure 7.8-3 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR FCC Limit value. The setting value and measured values are described in Table 7.2.1. At first, during 230s, LTE Band 41 transmitted. After 230s, the UMTS Band 5 transmitted for 400s. Both bands transmitted at maximum power throughout all intervals. However, for LTE Band 41, according to TAS algorithm, it operated under the SAR design Target 1.0W/kg. This result was computed that based on measured SAR result. Consequently, the average SAR in Figure 7.8-4 is under 1W/kg which is below the FCC limit of 1.6W/kg.

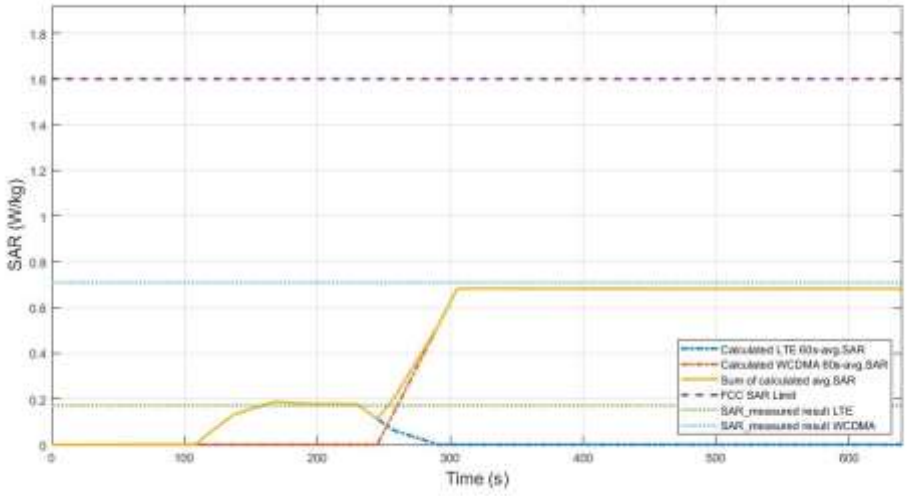

Figure 7.8-4 Total time-averaged SAR in TC14

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.607 W/kg
Device uncertainty	1 dB

7.9 WCDMA Time-varying Tx power

The test results in this section are obtained following the procedure in Section 4.3.7. The test cases correspond to TC14 in Table 6.1-1

TC19: WCDMA_Time_varying_Tx_power_Case1

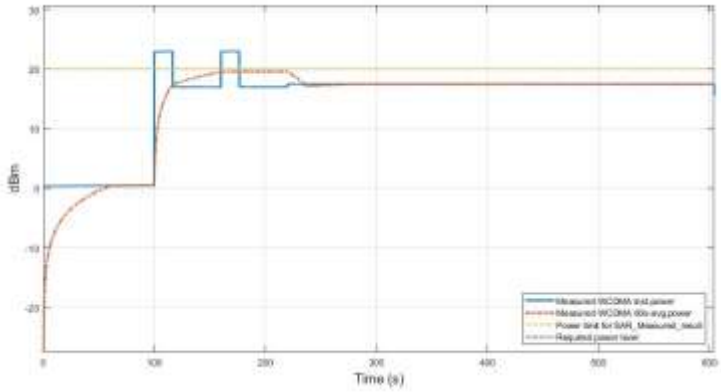

Figure 7.9-1 Conducted Transmitted power for WCDMA Band 2 in Test TC19

Figure 7.9-1 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR FCC Limit value. At the beginning a 0dBm power is requested for 100s, so the transmission is kept around this level. After those 100s a maximum power is requested, which yields the TAS to operate between that max power and a lower level since the Plimit is below the maximum power. After 80s, a power of half the Plimit is requested, so the transmission is kept fixed at that level. Consequently, the total average SAR shown in Figure 7.9-2 is about design target 1W/kg which is below the FCC limit of 1.6W/kg.

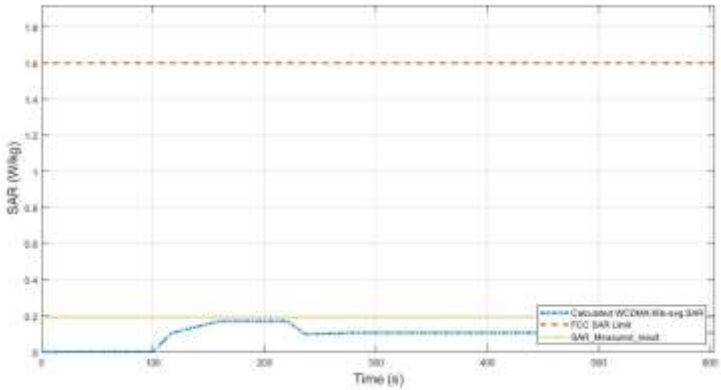

Figure 7.9-2 Total time-averaged SAR in TC19

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.165 W/kg
Device uncertainty	1 dB

TC10-2: WCDMA_Time_varying_Tx_power_Case2

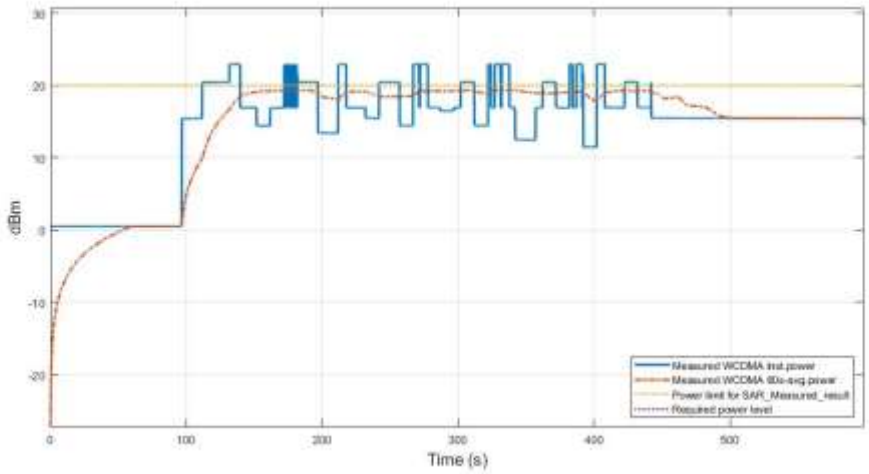

Figure 7.9-3 Conducted Transmitted power for WCDMA Band 2 in Test TC20

Figure 7.9-3 shows the instantaneous and time-averaged Tx power with test sequence B for WCDMA Band 2. In addition, Figure 7.9-3 shows that the moving-averaged Tx power is below the value of the targeted Plimit. Figure 7.9-4 shows the calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

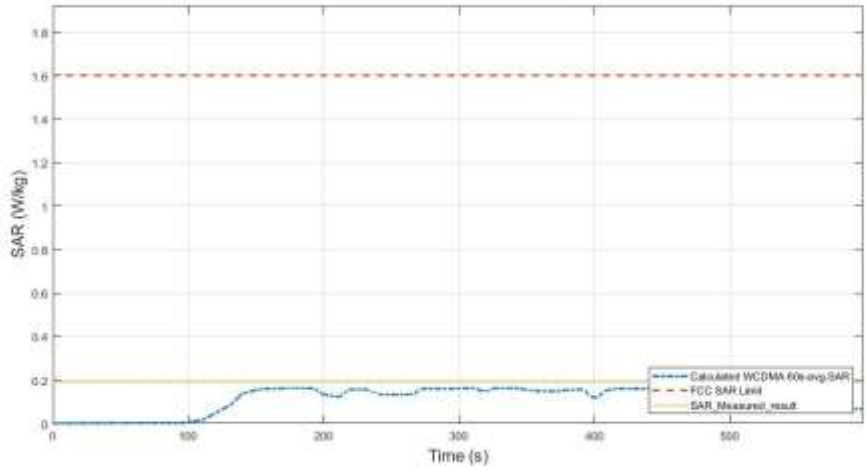

Figure 7.9-2 Total time-averaged SAR in TC20

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.163 W/kg
Device uncertainty	1 dB

7.10 2G Time-varying Tx power

The test results in this section are obtained following the procedure in Section 4.3.9. The test cases correspond to TC21-22 in Table 6.1-1

TC21: 2G_Time_varying_Tx_power_Case1

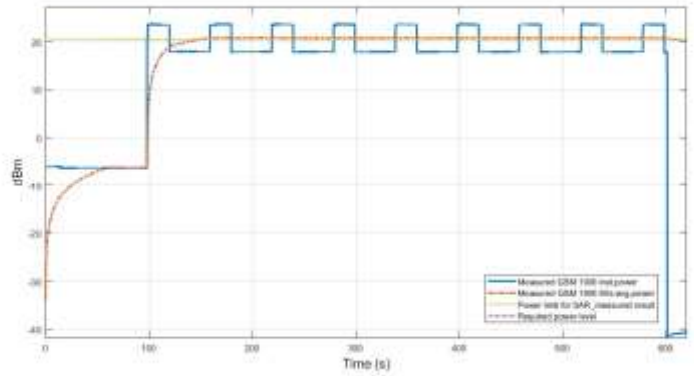

Figure 7.10-1 Conducted Transmitted power for 2G in Test [GSM1900] in TC21

Figure 7.10-1 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR FCC Limit value. At the beginning a 0dBm power is requested for 100s, so the transmission is kept low around this level. After those 100s a maximum power is requested, which yields the TAS to operate between that max power and a lower level since the Plimit is below the maximum power and continues for 500s. Consequently, the total average SAR shown in Figure 7.10-2 is below 1W/kg which is below the FCC limit of 1.6W/kg.

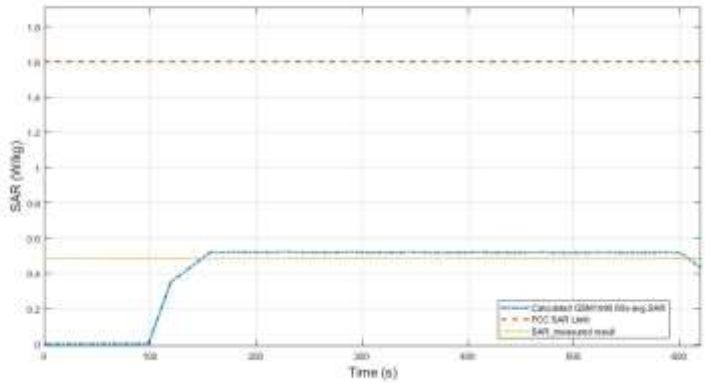

Figure 7.10-2 Total time-averaged SAR in TC21

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.525 W/kg
Device uncertainty	1 dB

TC22: 2G_Time_varying_Tx_power_Case2

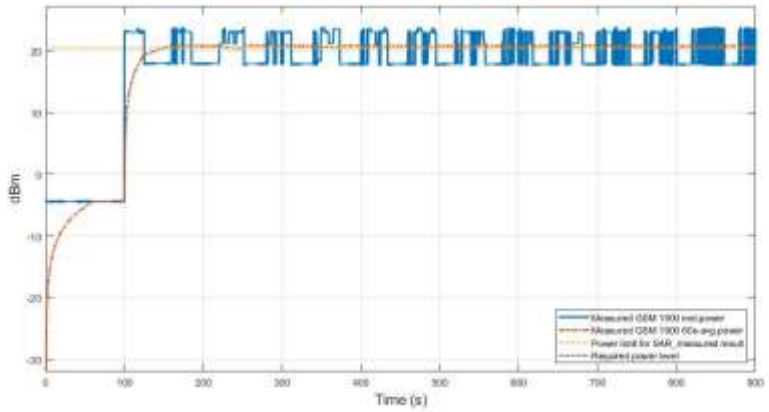

Figure 7.10-3 Conducted Transmitted power for 2G in Test [GSM1900] in TC22

Figure 7.10-3 shows the instantaneous and time-averaged Tx power with test sequence B for 2G (GSM1900). In addition, Figure 7.10-3 shows that the moving-averaged Tx power is below the value of the targeted Plimit. Figure 7.10-4 shows the calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

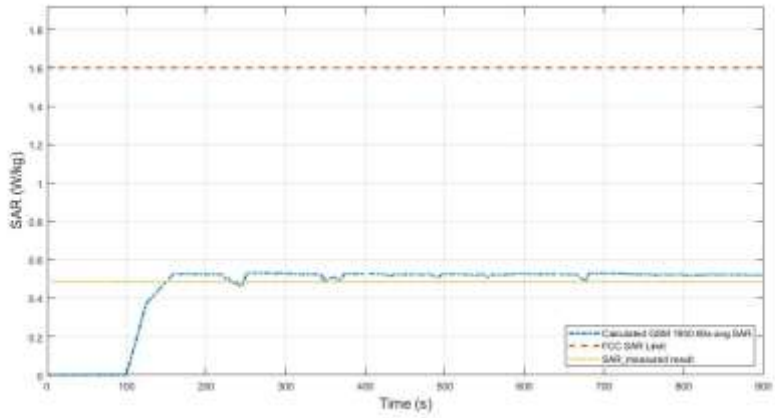

Figure 7.10-4Total time-averaged SAR in TC22

FCC 1gSAR limit	1.6 W/kg
Max 60s-time average 1gSAR (blue curve)	0.533 W/kg
Device uncertainty	1 dB

7.11 Antenna switching with spatial TAS

The test results in this section are obtained following the procedure in Section 4.4.1. The test cases correspond to TC24 in Table 6.1-1

TC24: SA_FR1_Ant_switching_Spatial_TAS

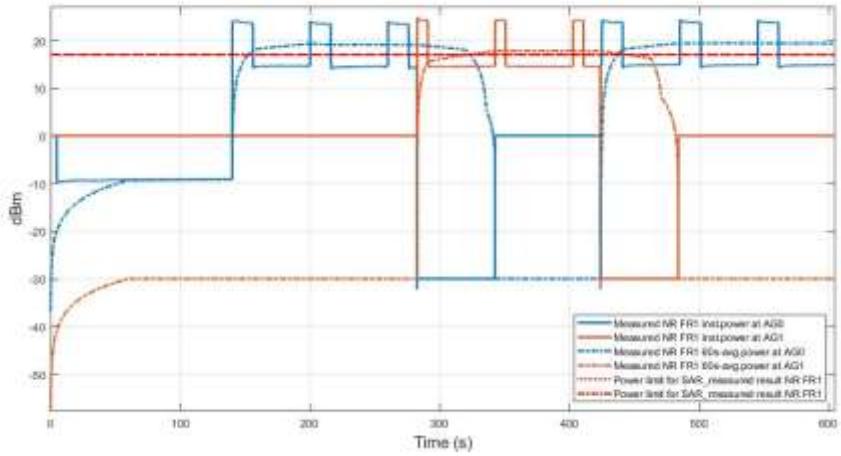

Figure 7.11-1 Conducted Transmitted power for NR Band 41 and NR band 77 in Test in TC24

Figure 7.11-1 shows the instantaneous and time-averaged conducted Tx power at antenna (Main2) with SA FR1 band n41 (AG0) and at antenna (Sub2) with SA FR1 band n77 (AG1). Transmission is initialized on AG0 where it was set for very low power for ~140s. After that, a maximum power is requested and the TAS starts to cycle. After ~150s a band change happens to SA FR1 n77 (AG1) which operates at antenna (Sub2) and a maximum power is requested. Since the coupling between AG0 and AG1 is 0, then transmission at Antenna (Sub2) will start from maximum power regardless of the transmission at Antenna (main2) and will continue transmission for ~150s. Next, another band change is done to the first band n41 and so an antenna switching to Antenna (Main2) happens where a maximum power is requested. Consequently, the total average SAR shown in Figure 7.11-2 at each antenna Group is below design target 1W/kg which is below the FCC limit of 1.6W/kg.

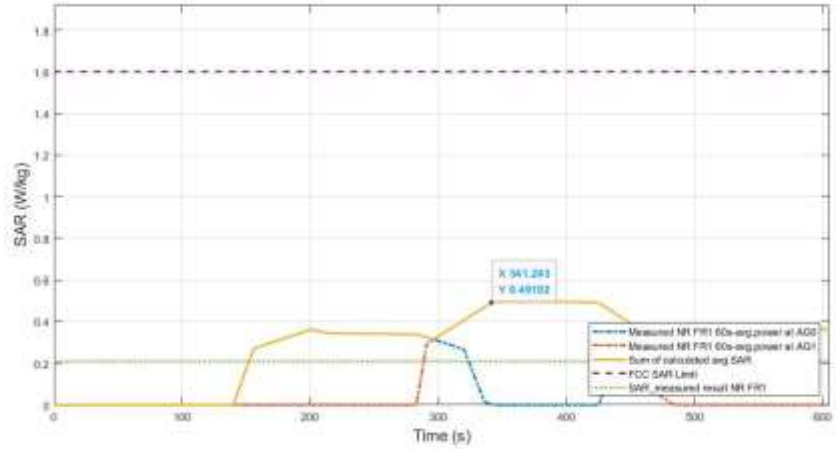

Figure 7.11-4 Total time-averaged SAR in TC24

FCC 1gSAR limit	1.6 W/kg
Sum of calculated average SAR (yellow curve)	0.491 W/kg
Device uncertainty	1 dB

7.12 NSA with spatial TAS

The test results in this section are obtained following the procedure in Section 4.4.2. The test cases correspond to TC25 in Table 6.1-1

TC25: NSA_Spatial_TAS

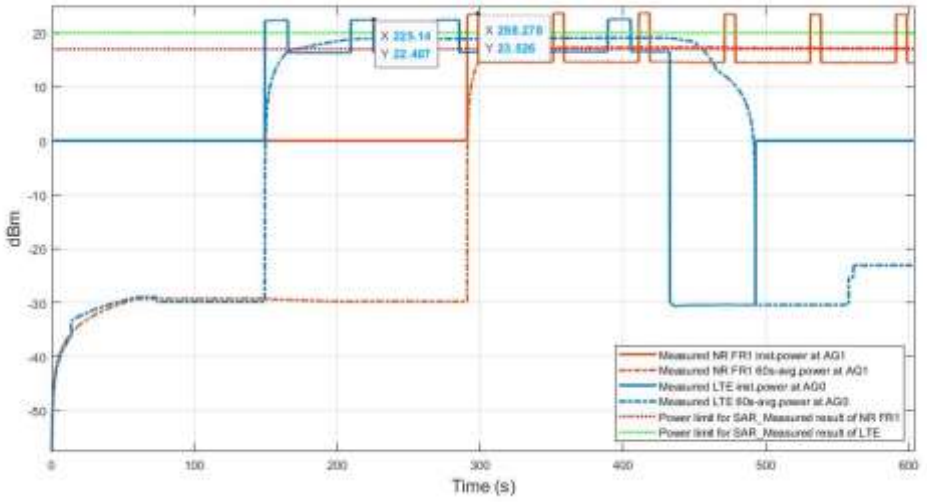

Figure 7.12-1 Conducted Transmitted power for LTE Band 66 and NR band n77 in Test in TC25

Figure 7.12-1 shows the instantaneous and time-averaged conducted Tx power for the NSA operation where LTE is transmitting at antenna (Main2) band B66 (AG0) and FR1 at antenna (Sub2) with band n77 (AG1). After the ENDC connection establishment, Both LTE and FR1 are set to no transmission for ~150s. Next, a transmission starts with LTE Band 66 (AG0) requesting full max power and no transmission for FR1 and continue for ~140s. After that, a maximum power is requested for FR1 band n77 (AG1) and transmission is done on Antenna (Sub2) and continue for ~140s. Since both AGs are fully uncoupled, each RAT will operate with full Plimit. Next, The LTE transmission is down while FR1 continues transmission. Consequently, the total average SAR is shown in Figure 7.14-2 at each antenna Group is about design target 1W/kg which is below the FCC limit of 1.6W/kg.

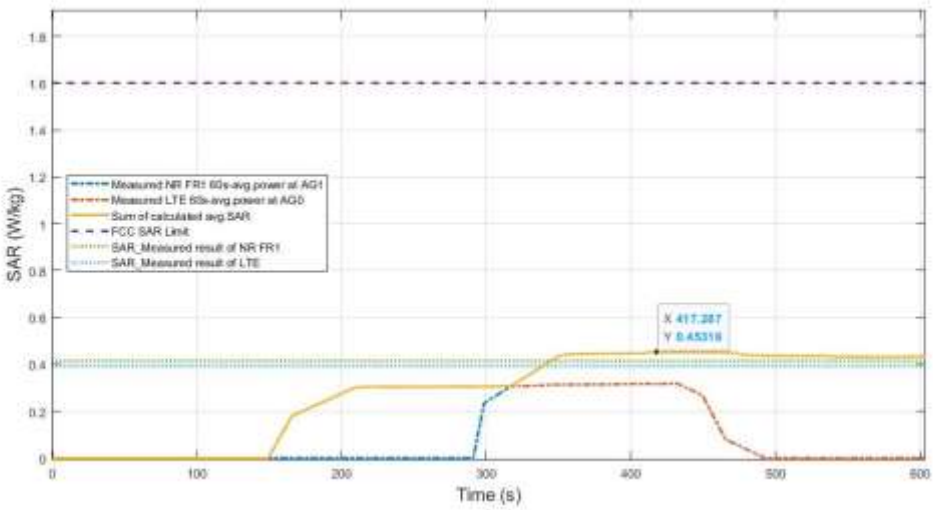

Figure 7.12-2 Total time-averaged SAR in TC25

FCC 1gSAR limit	1.6 W/kg
Sum of calculated average SAR (yellow curve)	0.453 W/kg
Device uncertainty	1 dB

7.13 NSA antenna switching with spatial TAS

The test results in this section are obtained following the procedure in Section 4.4.3. The test cases correspond to TC26 in Table 6.1-1

TC26: NSA_Ant_switching_Spatial_TAS

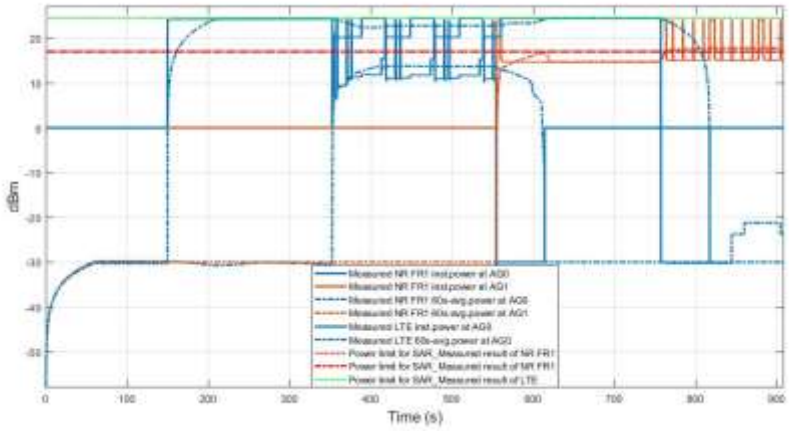

Figure 7.13-1 Conducted Transmitted power for LTE Band 26 and NR band n41, n77 in Test in TC26

Figure 7.13-1 shows the instantaneous and time-averaged conducted Tx power for a NSA operation where LTE is transmitting at antenna (Main1) band B26 (AG0) and FR1 at antennas (Main2, Sub2) with bands n41(AG0) and n77 (AG1) respectively. After the ENDC connection establishment, Both LTE band 26(Main1) and FR1 n41(Main2) are set to no transmission for ~150s. Next, a transmission starts with LTE requesting full max power and no transmission for FR1 and continue for ~200s. After that, a maximum power is requested for FR1 band n41 and transmission is done on Antenna (Main2) and continue for ~200s. Since LTE Band 26 and FR1 n41 are fully coupled, each RAT will operate, the SAR value was the highest instantaneously, but it can be seen that sum of average power in LTE Band 26(AG0) and FR1 n41(AG0) decreases again as soon as it is turned off. Next, FR1 will switch to band n77 (AG1) where FR1 requests maximum power and transmission continues for ~200s. Next, The LTE transmission is down while FR1 continues transmission. Consequently, the total average SAR shown in Figure 7.13-2 at each antenna group is about design target 1W/kg which is below the FCC limit of 1.6W/kg.

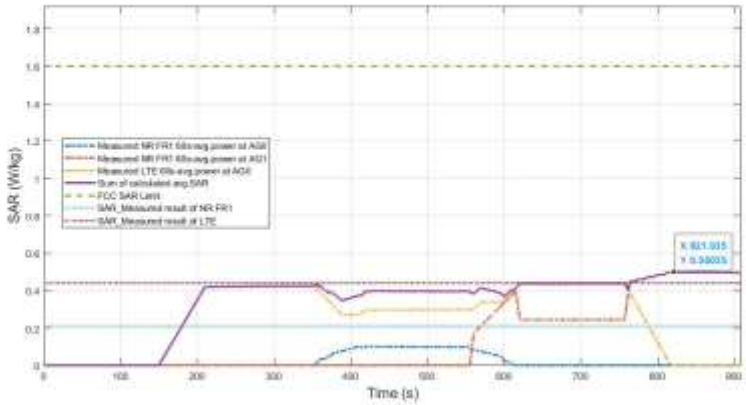

Figure 7.13-2 Total time-averaged SAR in TC26

FCC 1gSAR limit	1.6 W/kg
Sum of calculated average SAR (purple curve)	0.500
Device uncertainty	1 dB

*note

1. In this case, all result of test was computed that based on measured SAR result.
2. Every measured part 1 results were below the SAR design target 1.0W/kg.
3. TAS algorithm validation test cases were configured based on the measurement test cases of Part 1.

8. Conclusions

Samsung Time-Averaging SAR (TAS) feature employed in A has been validated through conducted power measurement as well as SAR measurement. As demonstrated in this report, TAS feature limit the transmit power effectively and shows that SAR value does not exceed 1.6 W/kg for all the transmission scenarios.

9. Equipment List

Manufacturer	Type / Model	S/N	Calib. Date	Calib.Interval	Calib.Due
Narda	Directional Coupler / 4216-10	01490	11/28/2023	Annual	11/28/2024
Narda	Directional Coupler / 4216-10	01489	11/28/2023	Annual	11/28/2024
HP	Power Divider/11636B	50659	05/26/2023	Annual	05/26/2024
HP	Power Divider/11636B	58698	01/15/2024	Annual	01/15/2025
RFCOREA	2Way Spliter	473842	12/13/2023	Annual	12/13/2024
RFCOREA	2Way Spliter	473841	12/13/2023	Annual	12/13/2024
Anritsu	Radio Communication Analyzer / MT8821C	6262044720	11/28/2023	Annual	11/28/2024
Anritsu	Radio Communication Analyzer / MT8821C	6262116770	08/02/2023	Annual	08/02/2024
Anritsu	Radio Communication Test Station / MT8000A	6262036812	11/28/2023	Annual	11/28/2024
Anritsu	Power Meter / ML2496A	2041001	11/28/2023	Annual	11/28/2024
Anritsu	Power Sensor / MA2475D	1911225	11/28/2023	Annual	11/28/2024
Anritsu	Power Sensor / MA2475D	1911226	11/28/2023	Annual	11/28/2024

10. References

The following documents contain reference in this technical document.

[1] [ForOEM][Samsung+S.LSI]+Time+average+SAR+algorithm(FCC)_v.2.7_v0.2_PDF_v0.0

Appendix A. Test sequence

1.1 Test sequence is generated based on below parameters of the DUT:

1. Measured maximum power (P_{max})
2. Measured Tx power (P_{limit}) to satisfy SAR Compliance
3. Setup time to make SAR Remaining be full
4. Do test according to test sequence

1.2 Test Sequence A waveform:

Based on the parameters above, the test sequence A is generated with one or two levels where one of the levels is maximum power level (Pmax) which is applied at least for 100s. Based on the second level this test sequence is sub-categorized into four different sequences used

a. Test Sequence A.i where after Pmax, a second level of Plimit is requested till the end of the test

b. Test Sequence A.ii where after Pmax, a second level of Pmax-3dB is requested till the end of the test

c. Test Sequence A.iii where after Pmax, a second level of Plimit-3dB is requested till the end of the test

d. Test Sequence A.iv where only Pmax is requested till the end of the test

1.3 Test Sequence B waveform:

Based on the parameters above, the Test Type B is generated with pre-defined power levels, which

is described in Table 1.3.1

Table 1.3.1 Table of test sequence B

Time duration (second)	Power level (dB)
15	Plimit – 5
20	Plimit
20	Plimit + 5
10	Plimit – 6
20	Pmax
15	Plimit
15	Plimit -7
20	Pmax
10	Plimit-5
15	Plimit
10	Plimit-6
20	Plimit + 5
10	Plimit – 4
15	Plimit
10	Plimit – 6
20	Pmax
15	Plimit-8
15	Plimit
20	Pmax
10	Plimit – 9
20	Plimit + 5
20	Plimit
15	Plimit – 5